

# AI ASIC: Design and Practice (ADaP)

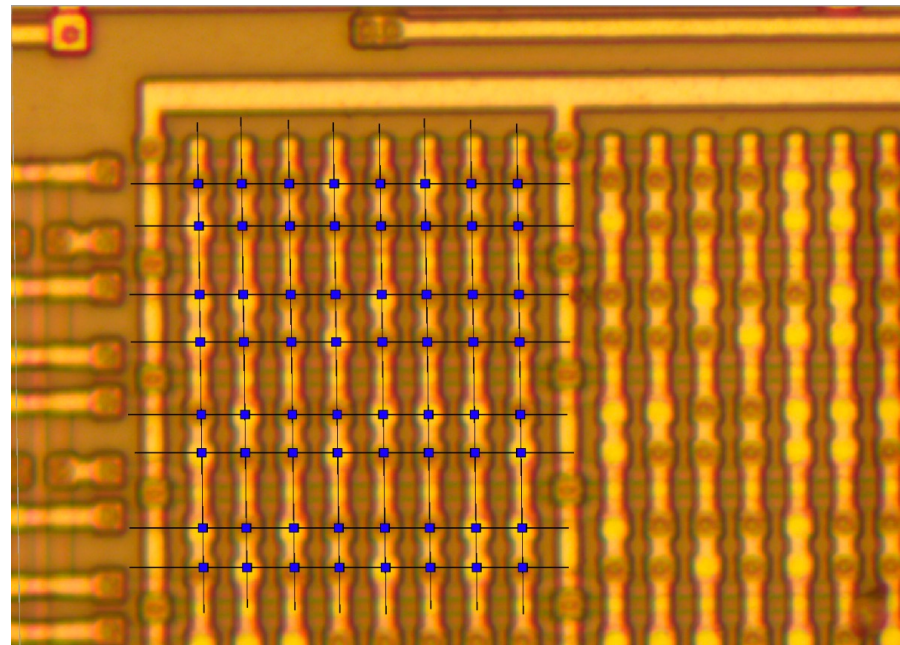
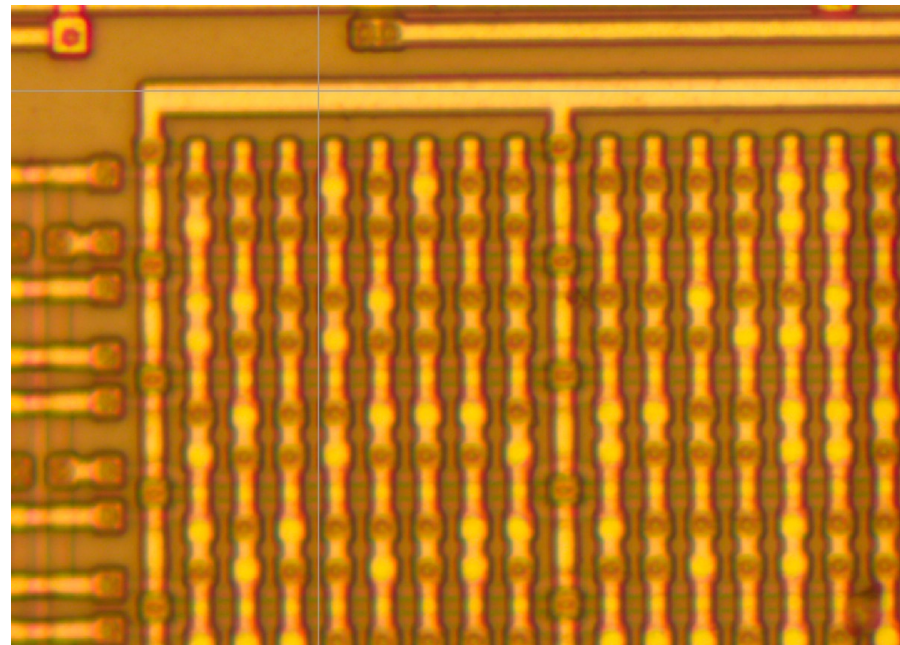
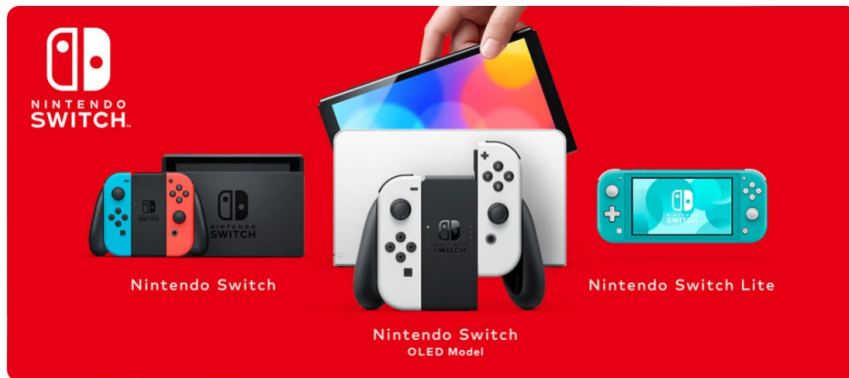
Fall 2023

## Memory Technologies

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# Introduction





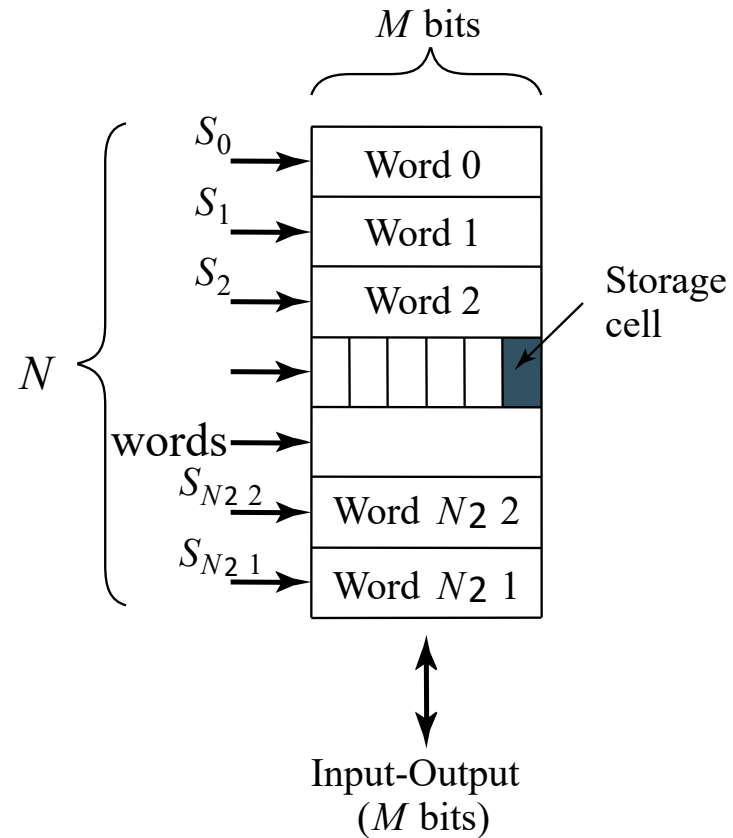
# Outline

- Memory Types
- Memory Organization
- ROM design
- RAM design
- PLA design

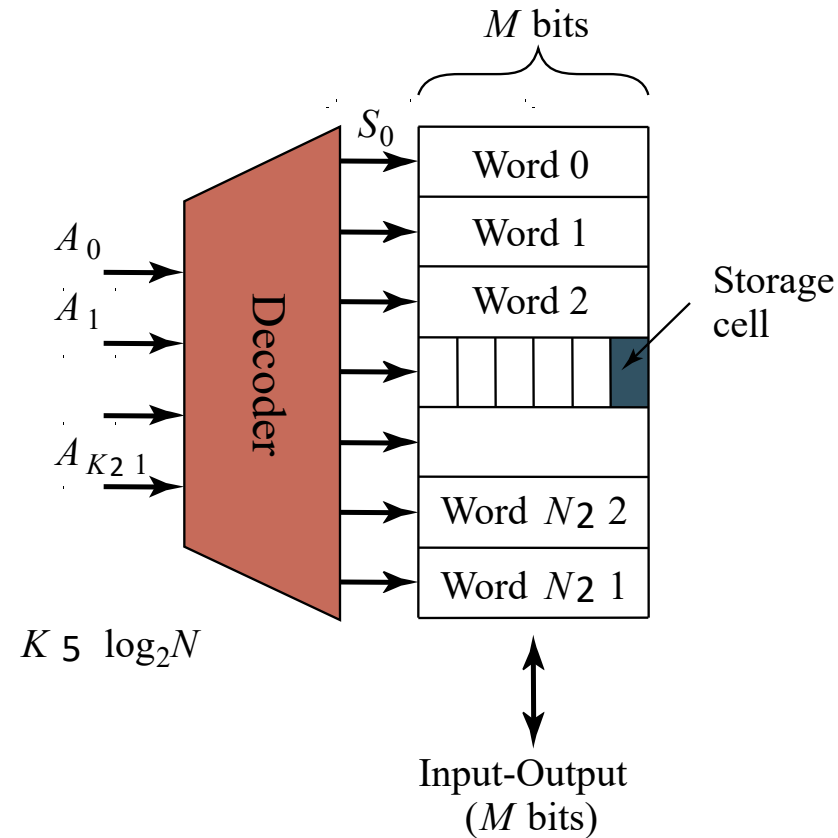
# Memory Types

Read-Write Memory		Non-Volatile Read-Write Memory	Read-Only Memory
Random Access	Non-Random Access	EPROM E <sup>2</sup> PROM  FLASH  RRAM <i>MRAM</i> <i>PCM</i>	Mask-Programmed Programmable (PROM)
SRAM  DRAM	FIFO  LIFO Shift Register  CAM		

# Memory Spatial Abstraction

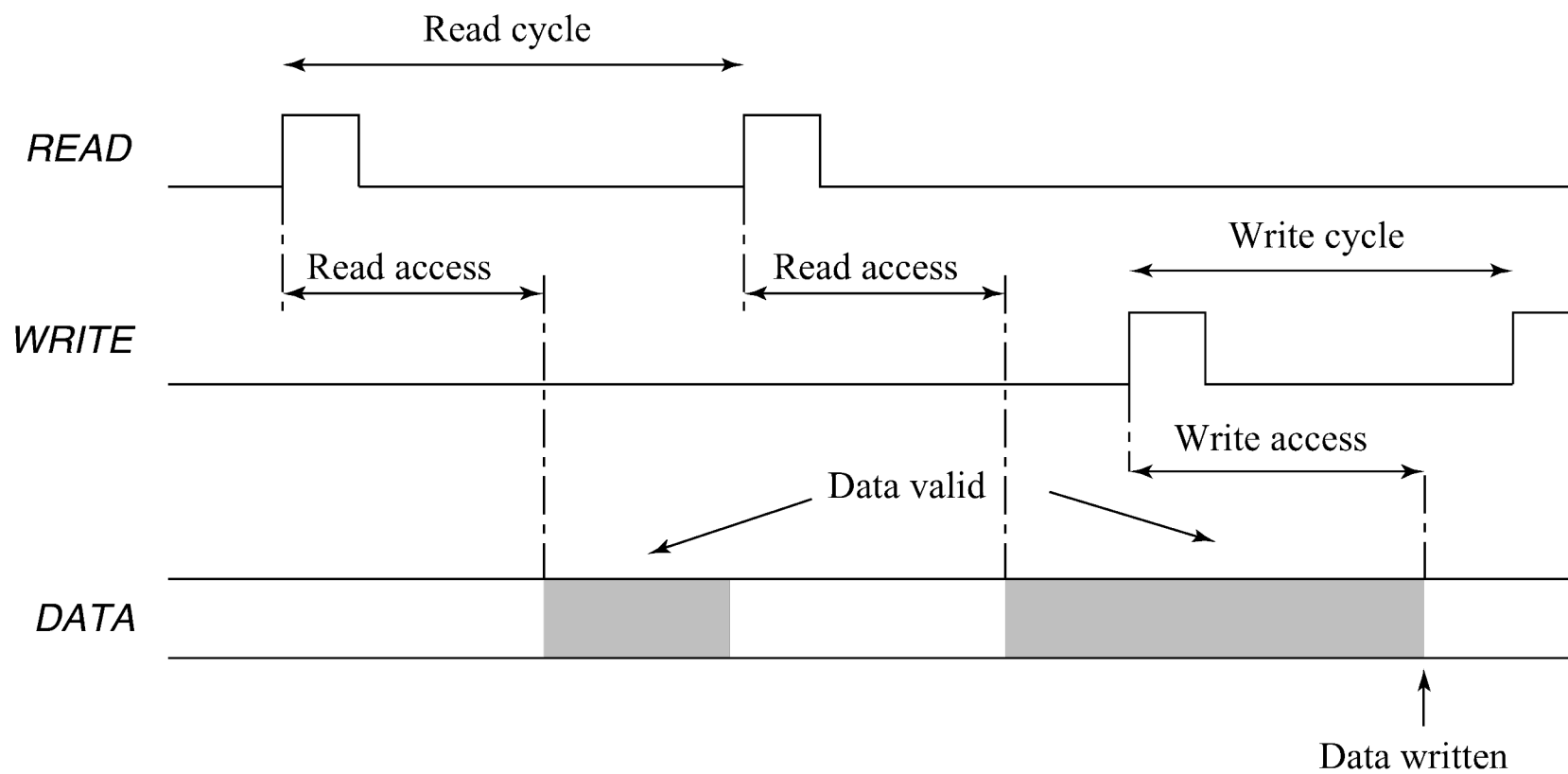


Intuitive architecture for  $N \times M$  memory  
Too many select signals:  
 $N$  words ==  $N$  select signals



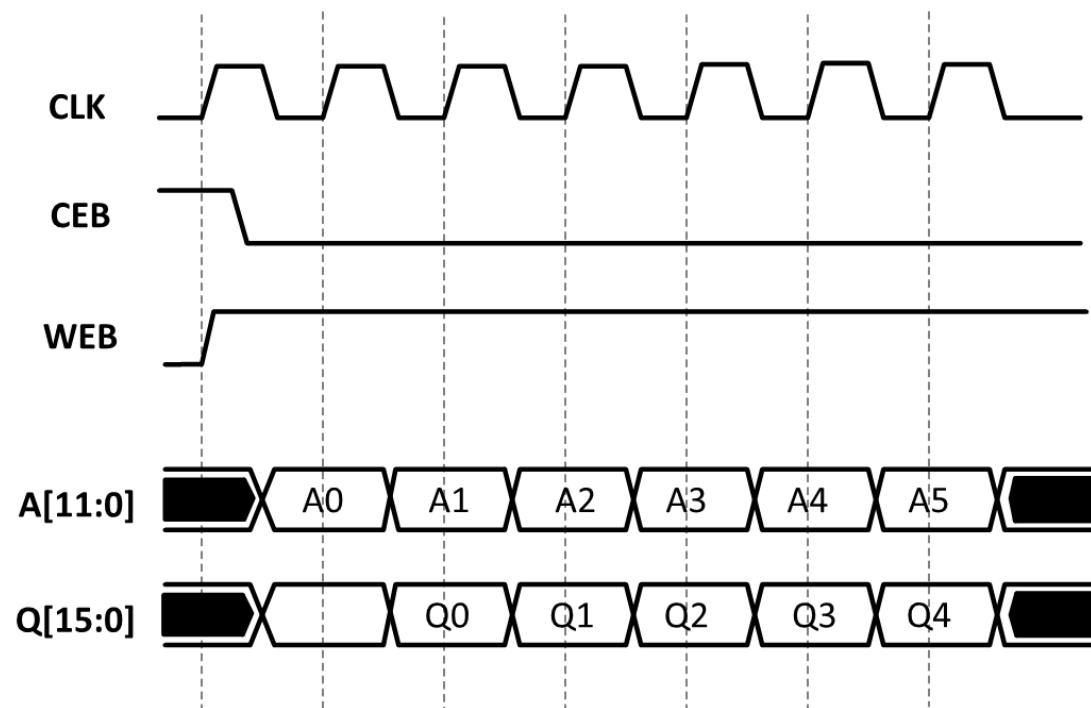
Decoder reduces the number of select signals  
 $K = \log_2 N$

# Memory Timing Behavior

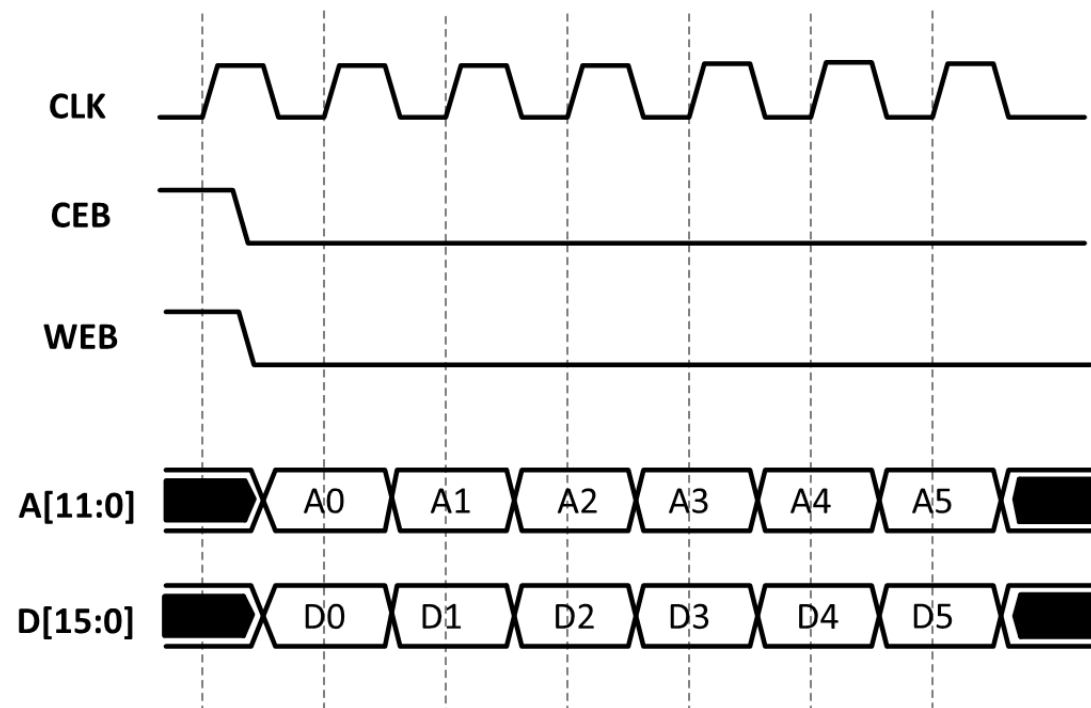


# Memory Timing Behavior

Normal Mode Read

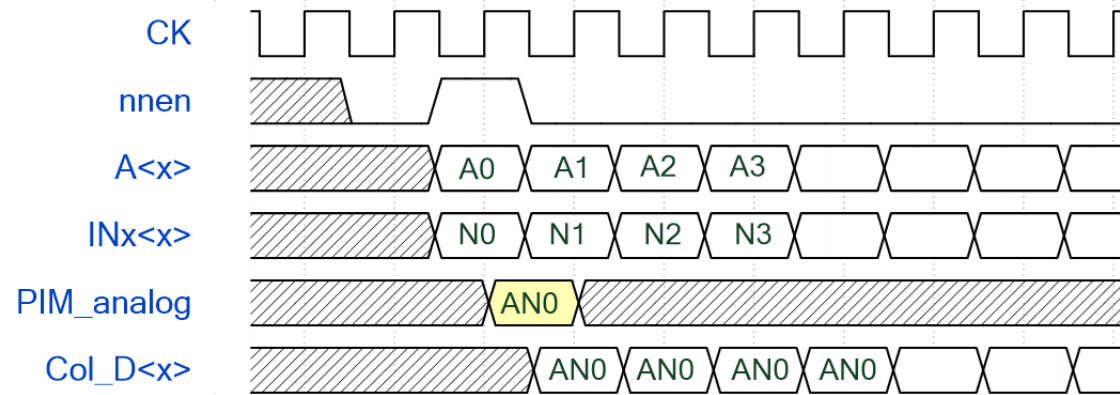


Normal Mode Write

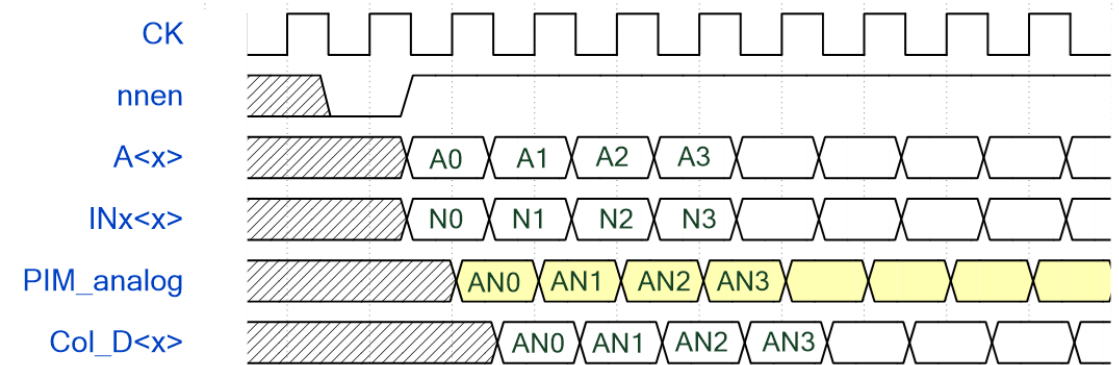


# Memory Timing Behavior / Compute-In-Memory

**Burst condition**



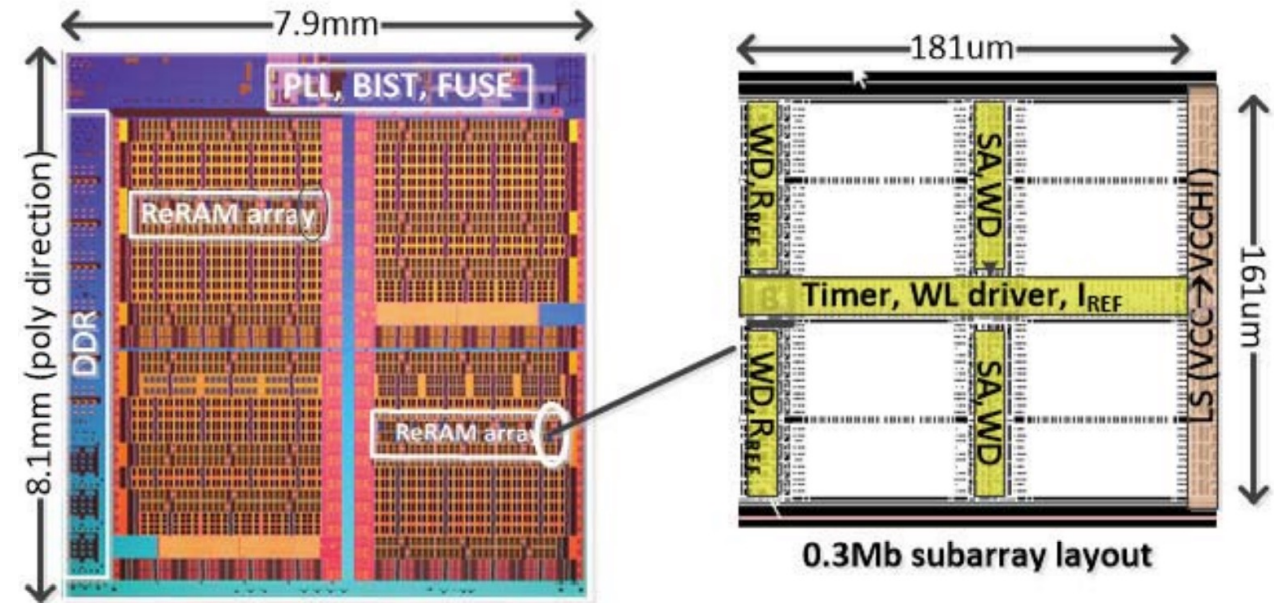
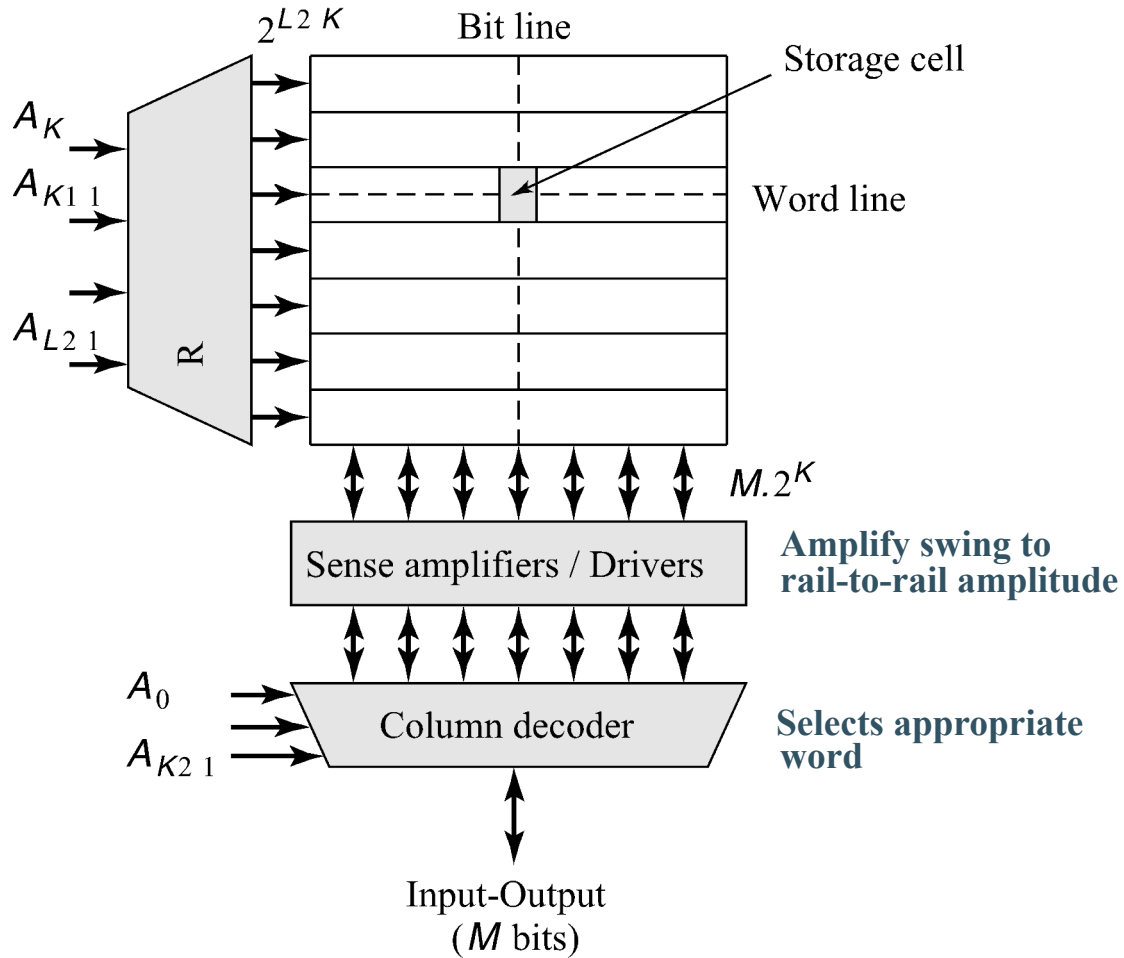
**Continuous condition**



- Add additional (compute mode) inputs
- Perhaps additional address bits



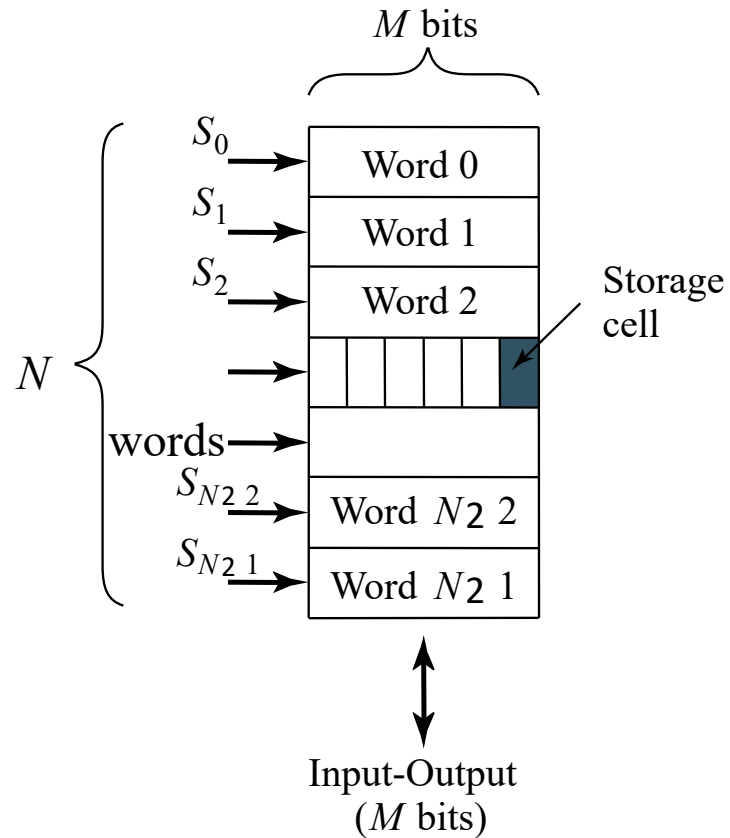
# Memory Architecture



How it can achieve large capacity?

Jain, Pulkit, et al. "13.2 A 3.6 Mb 10.1 Mb/mm<sup>2</sup> embedded non-volatile ReRAM macro in 22nm FinFET technology with adaptive forming/set/reset schemes yielding down to 0.5 V with sensing time of 5ns at 0.7 V." *2019 IEEE International Solid-State Circuits Conference-(ISSCC)*. IEEE, 2019.

# Memory Address



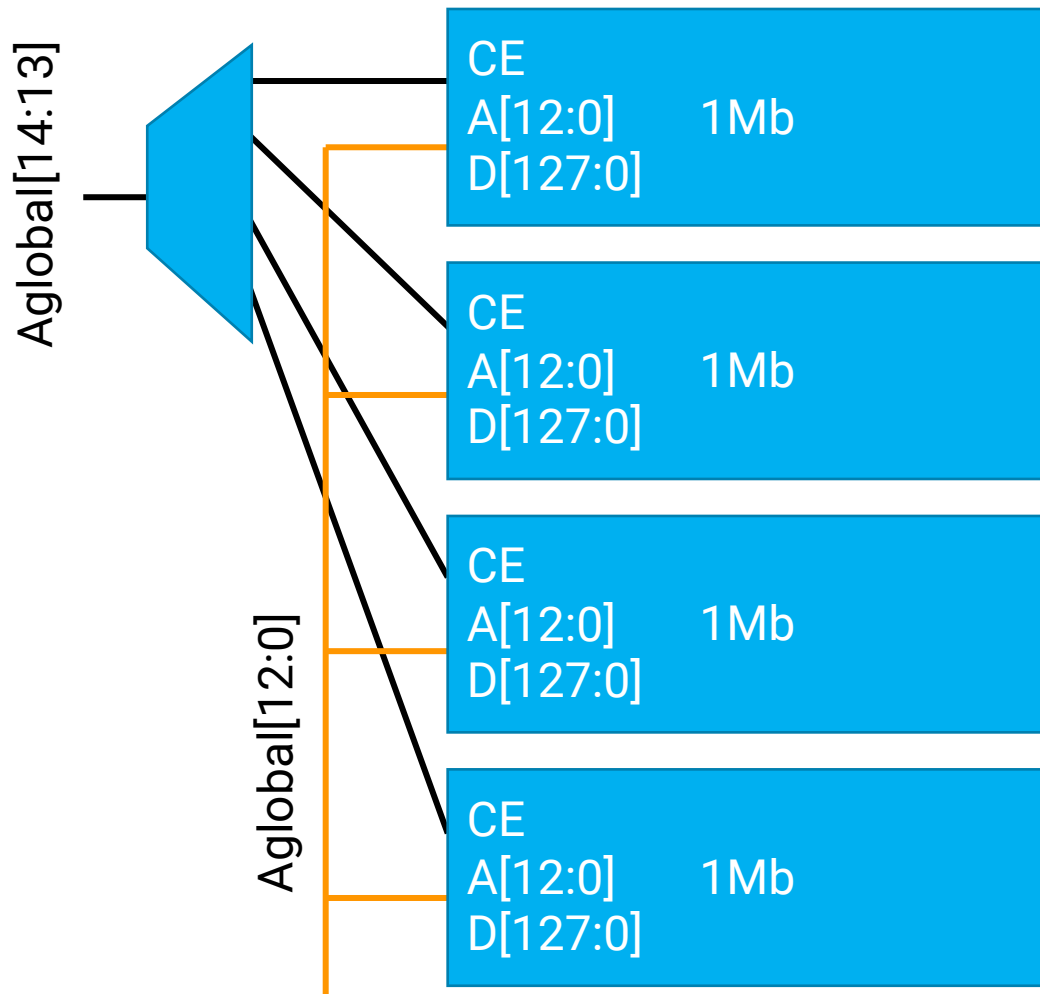
Each memory I/O bit width is 128bit

For 1Mb memory, what is the range of memory address?

$$\begin{aligned} & 1\text{Mb}/128\text{b} \\ &= (2^{20} \text{ bit}) / (2^7 \text{ bit}) \\ &= 2^{13} \end{aligned}$$

13-wire address is necessary

# Memory Architecture (inside a memory block)



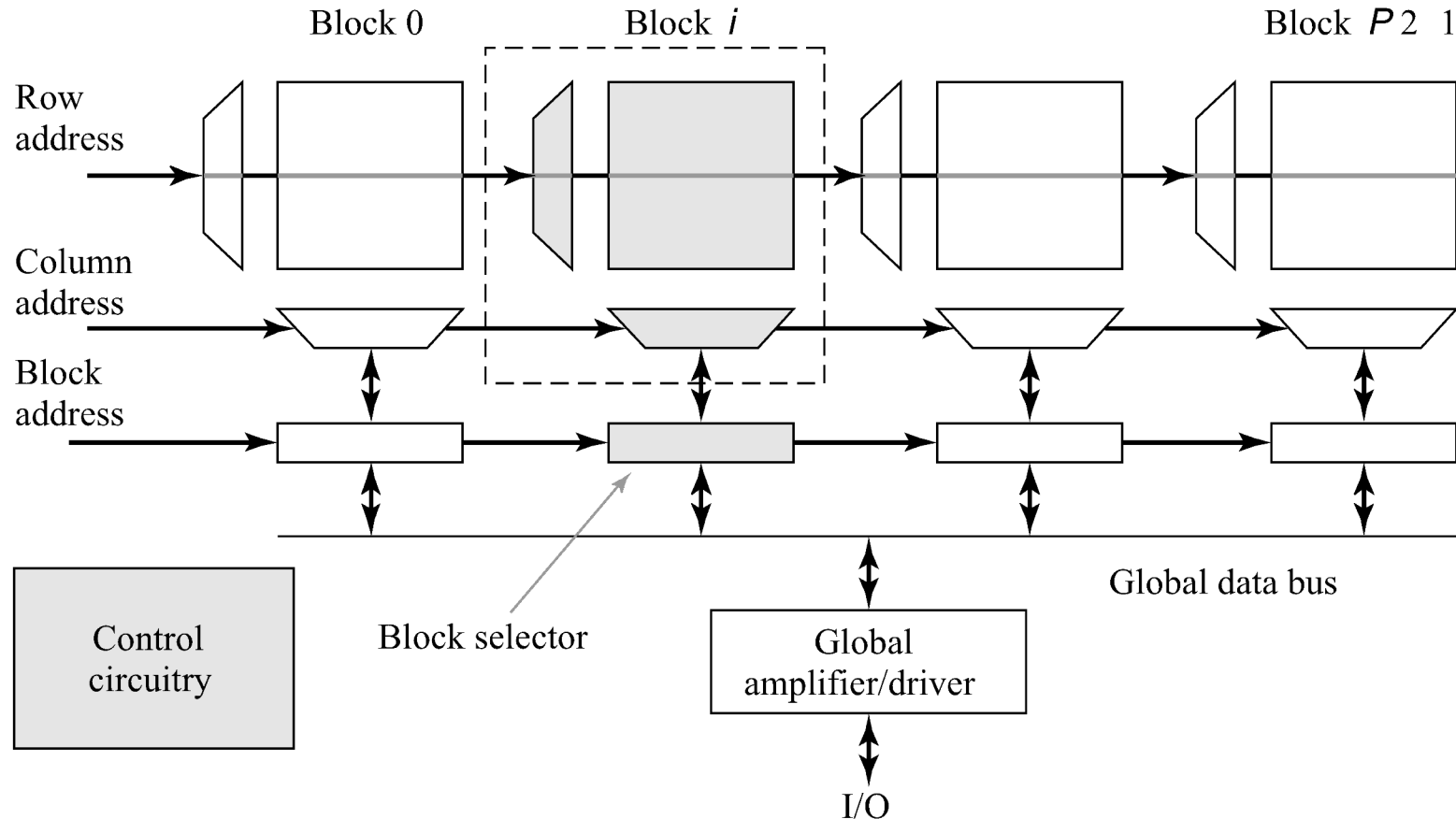
Assume 1Mb is one subarray

Configuration:

- Memory I/O bit width is 128b
- 1Mb/subarray
- Address width: 13b

How get 4Mb memory?

# Hierarchical Memory Architecture



Advantages:

1. Shorter wires within blocks
2. Block address activates only 1 block => power savings

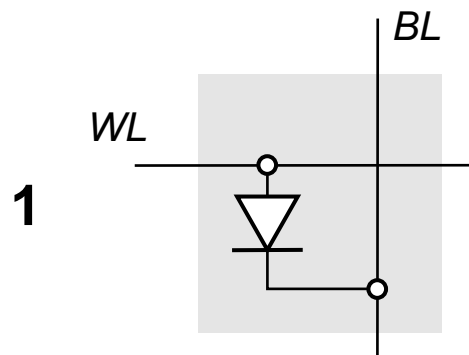
- Read-Only-Memory (ROM)
- Random-Access-Memory (RAM) : Read/Write Memory
  - SRAM
  - DRAM

Before we introduce them, think first: what are good memories?

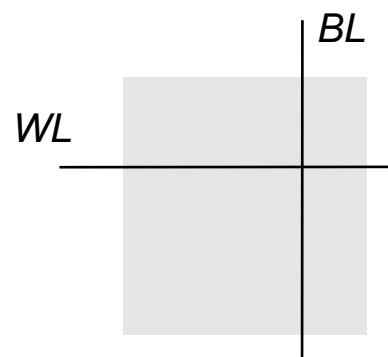
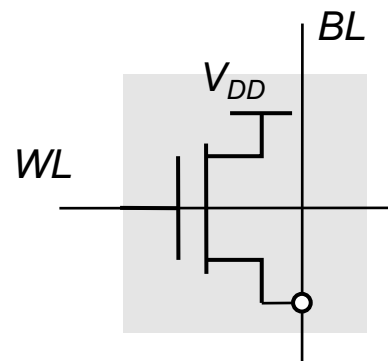
Density, R/W Speed, Endurance, Retention, Nonvolatility, ...

- Read-Only-Memory (ROM)
- Random-Access-Memory (RAM) : Read/Write Memory
  - SRAM
  - DRAM

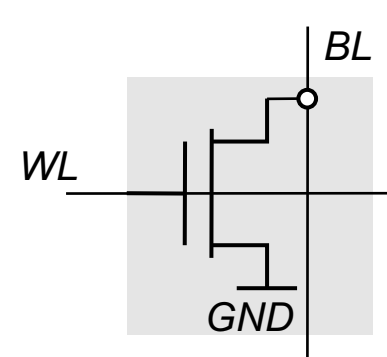
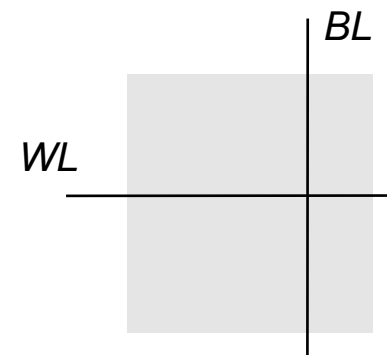
# ROM Cells



Diode ROM

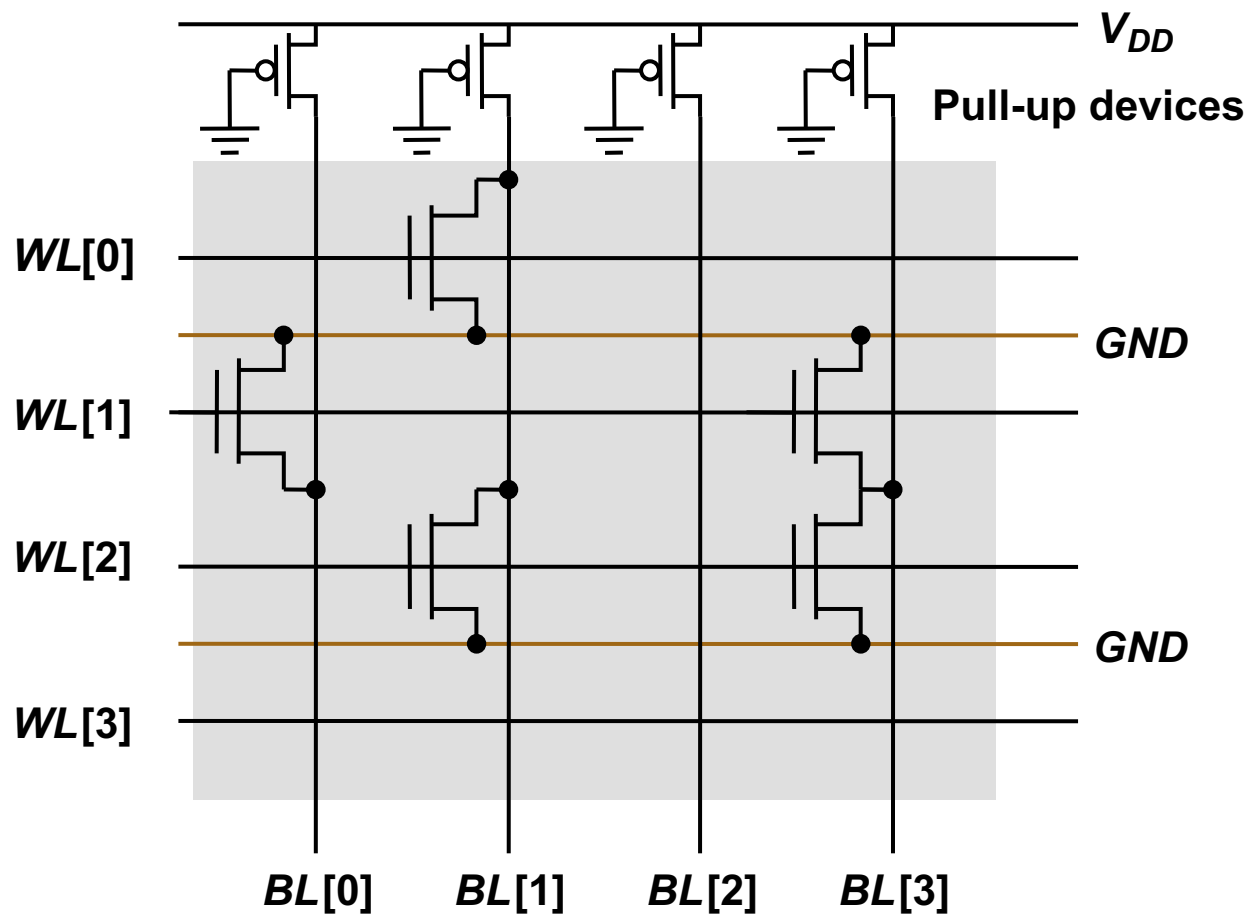
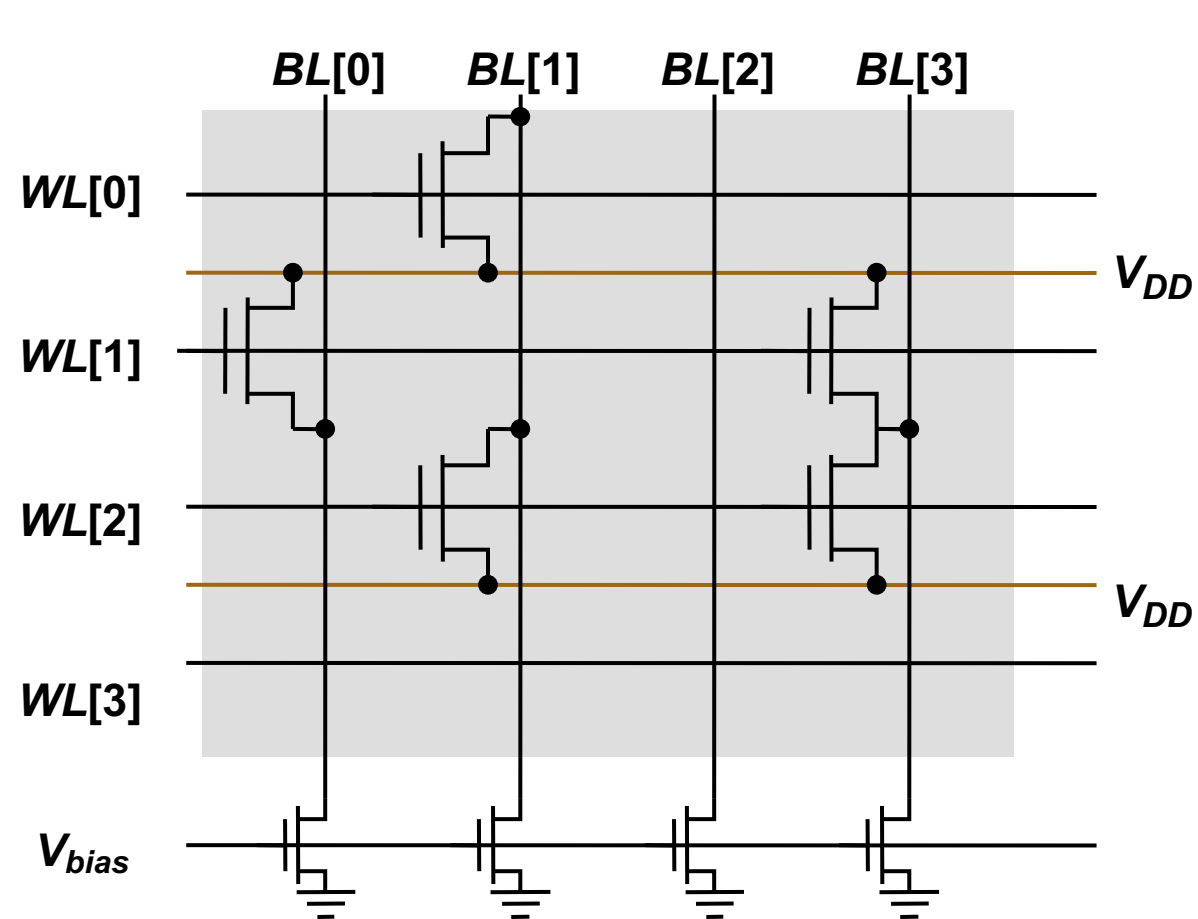


MOS ROM 1



MOS ROM 2

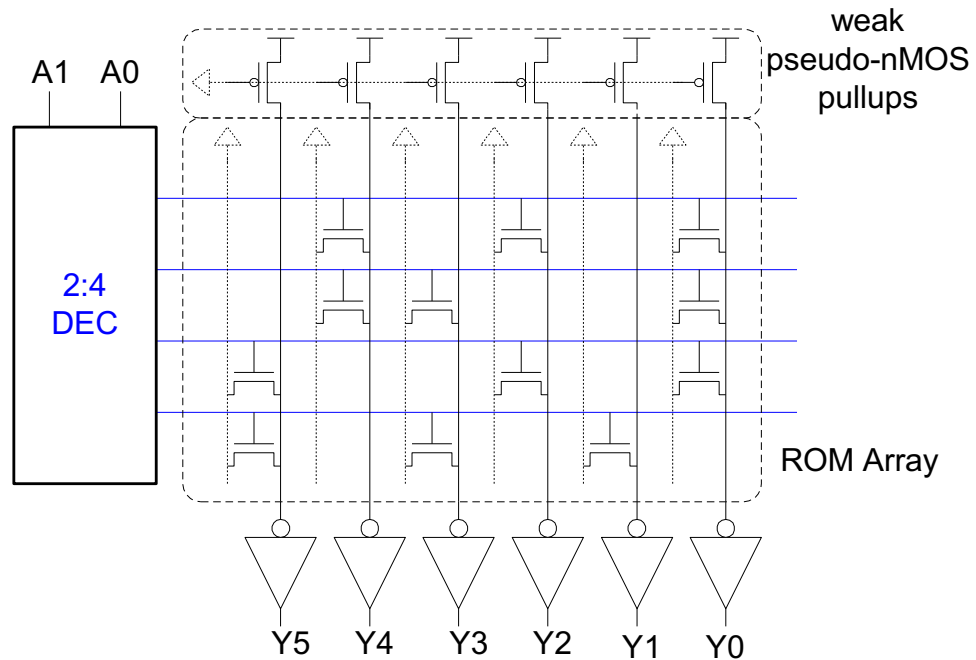
# MOS ROM





# MOS ROM Example

- 4-word x 6-bit ROM
  - Represented with dot diagram
  - Dots indicate 1's in ROM



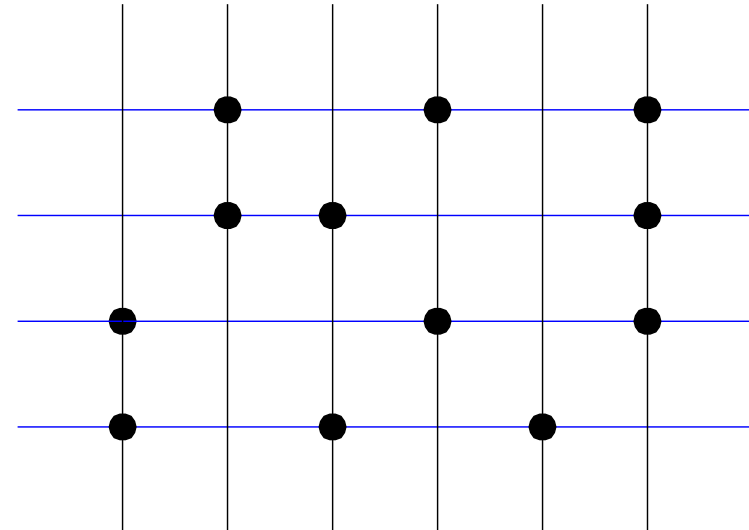
Looks like 6 4-input pseudo-nMOS NORs

Word 0: 010101

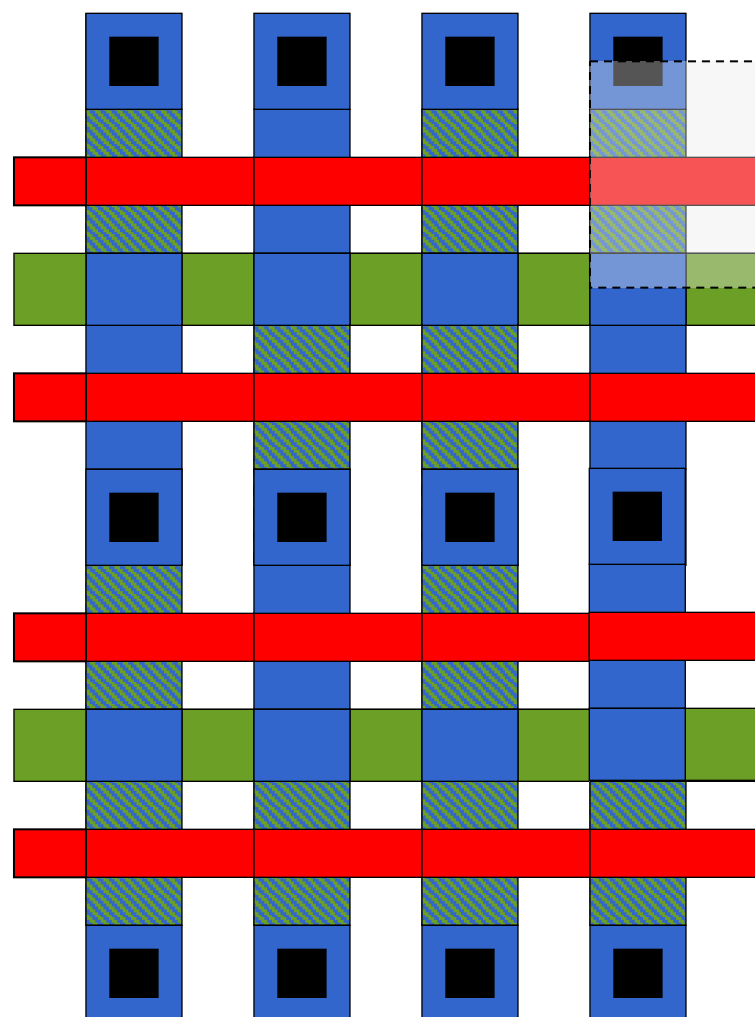
Word 1: 011001

Word 2: 100101

Word 3: 101010







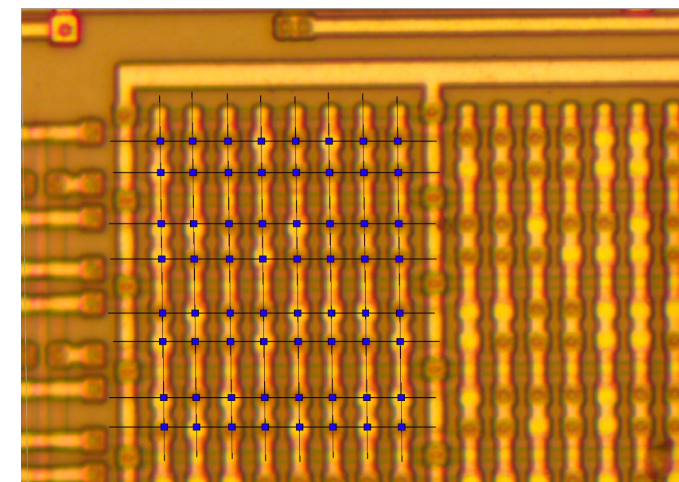
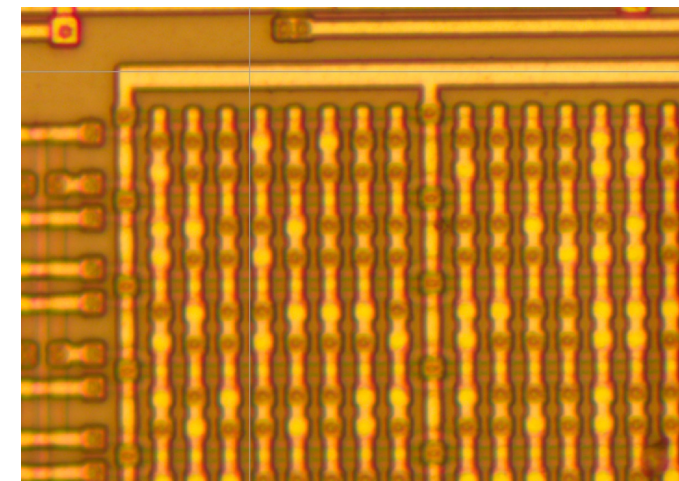
# Layout



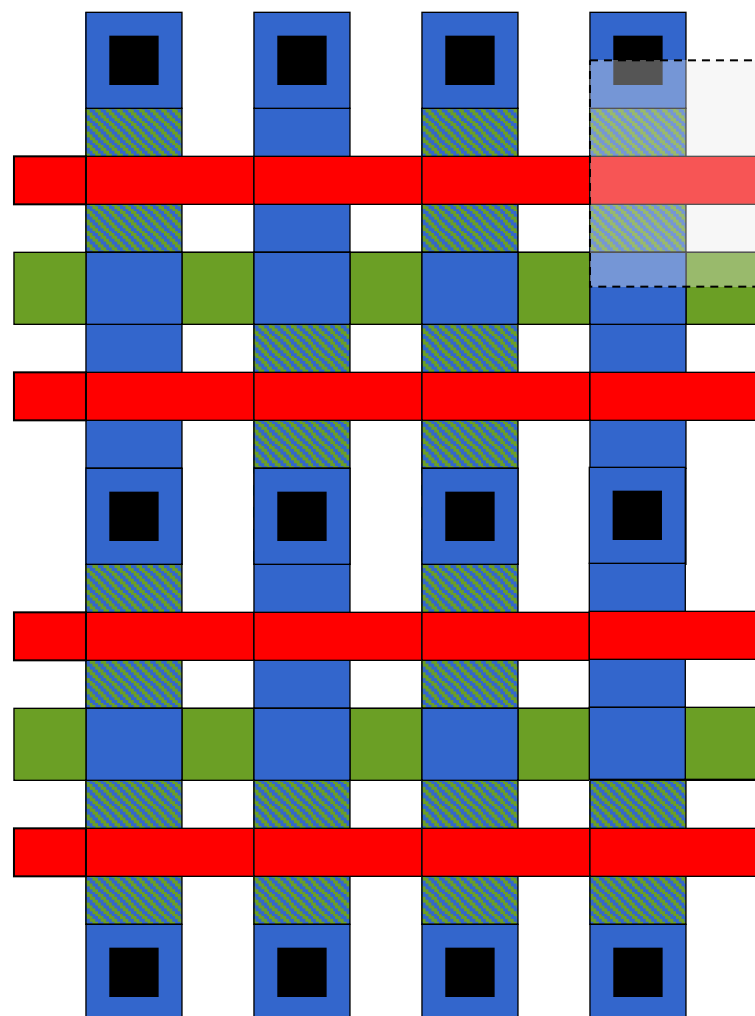
Cell ( $19f \times 14f$ )

Programmming using the  
Active Layer Only

-  Polysilicon
-  Metal1
-  Diffusion
-  Metal1 on Diffusion



# Layout




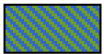


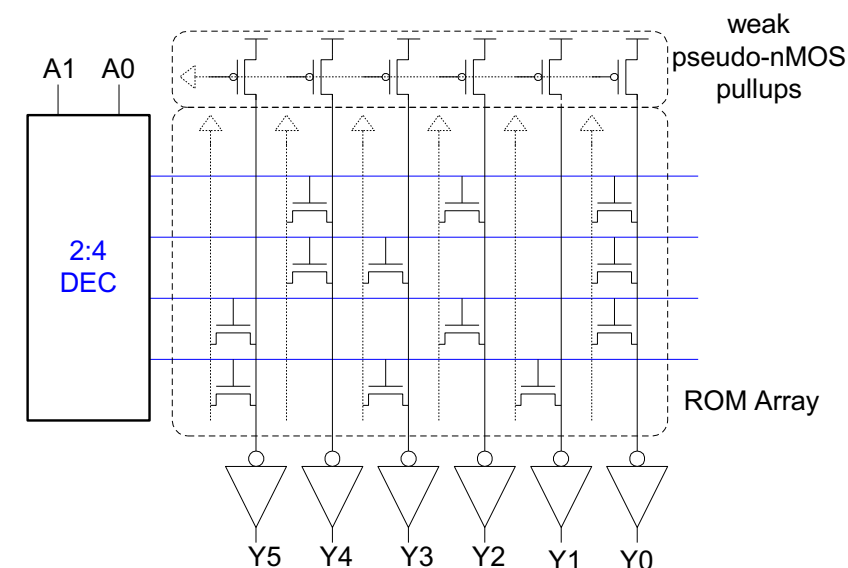
Cell ( $19f \times 14f$ )

$f$ : feature size

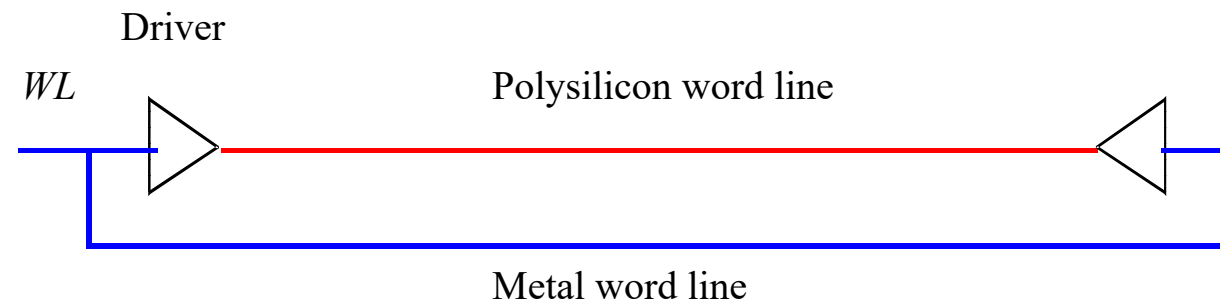
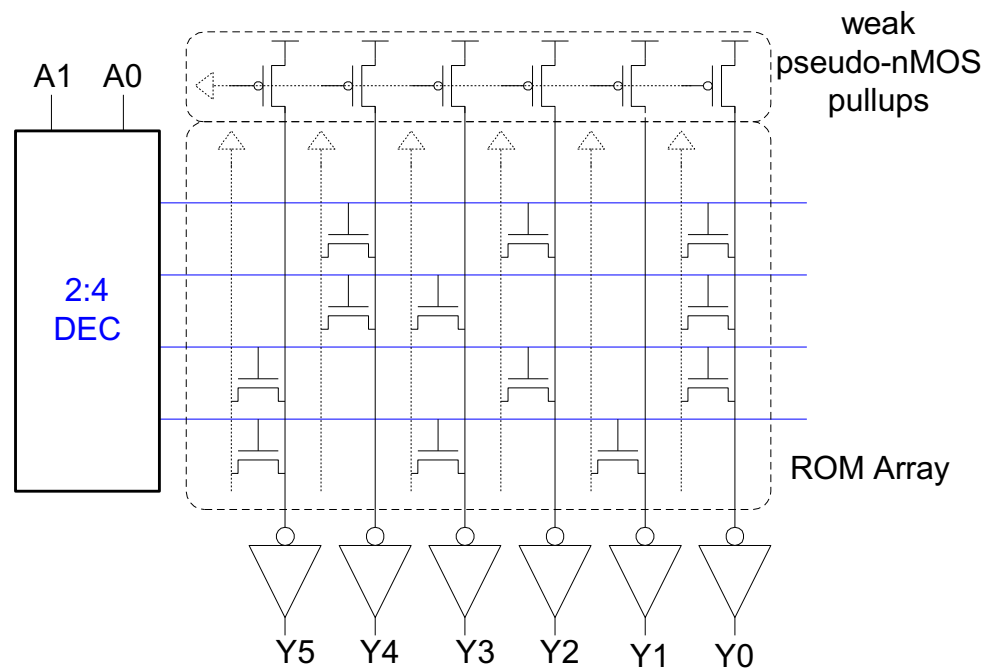
Programmming using the  
Active Layer Only

Q: Can this array  
expand to infinite size?

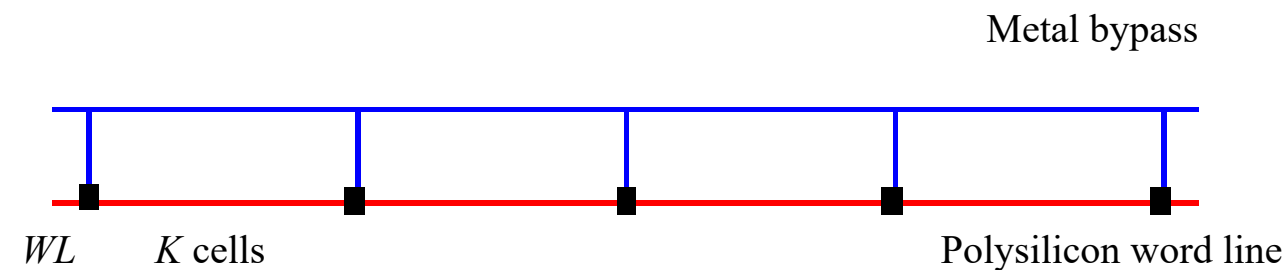
-  Polysilicon
-  Metal1
-  Diffusion
-  Metal1 on Diffusion



# Decreasing Word Line Delay



(a) Driving the word line from both sides



(b) Using a metal bypass

- Read-Only-Memory (ROM)
- Random-Access-Memory (RAM) : Read/Write Memory
  - SRAM
  - DRAM

## ❑ **STATIC (SRAM)**

**Data stored as long as supply is applied**

**Large (6 transistors/cell)**

**Fast**

**Differential**

## ❑ **DYNAMIC (DRAM)**

**Periodic refresh required**

**Small (1-3 transistors/cell)**

**Slower**

**Single Ended**

## ❑ **STATIC (SRAM)**

**Data stored as long as supply is applied**

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## ❑ **DYNAMIC (DRAM)**

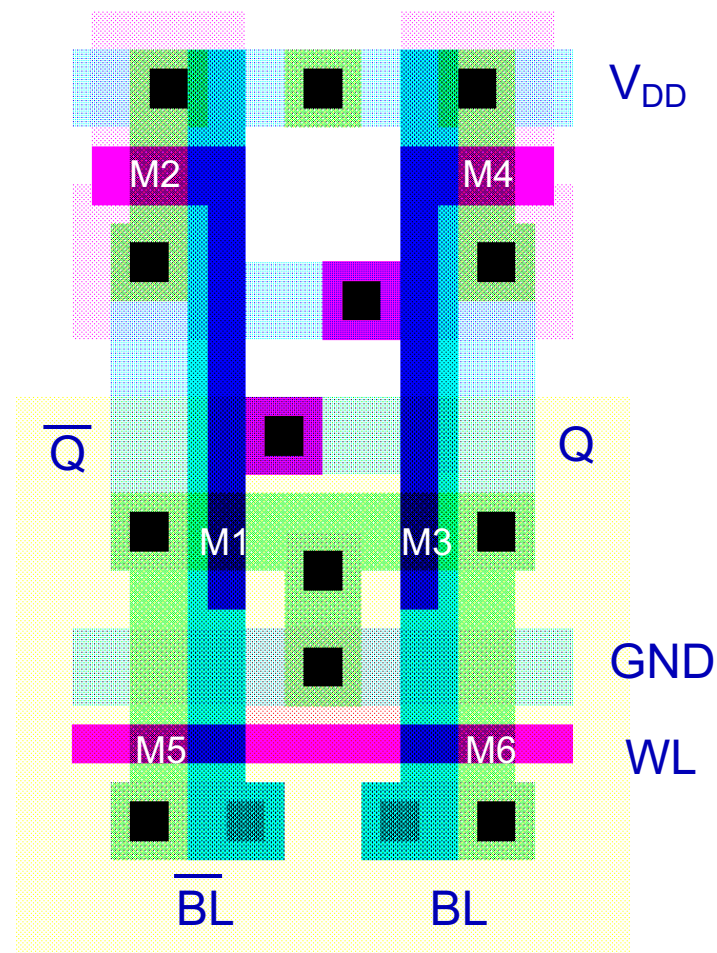
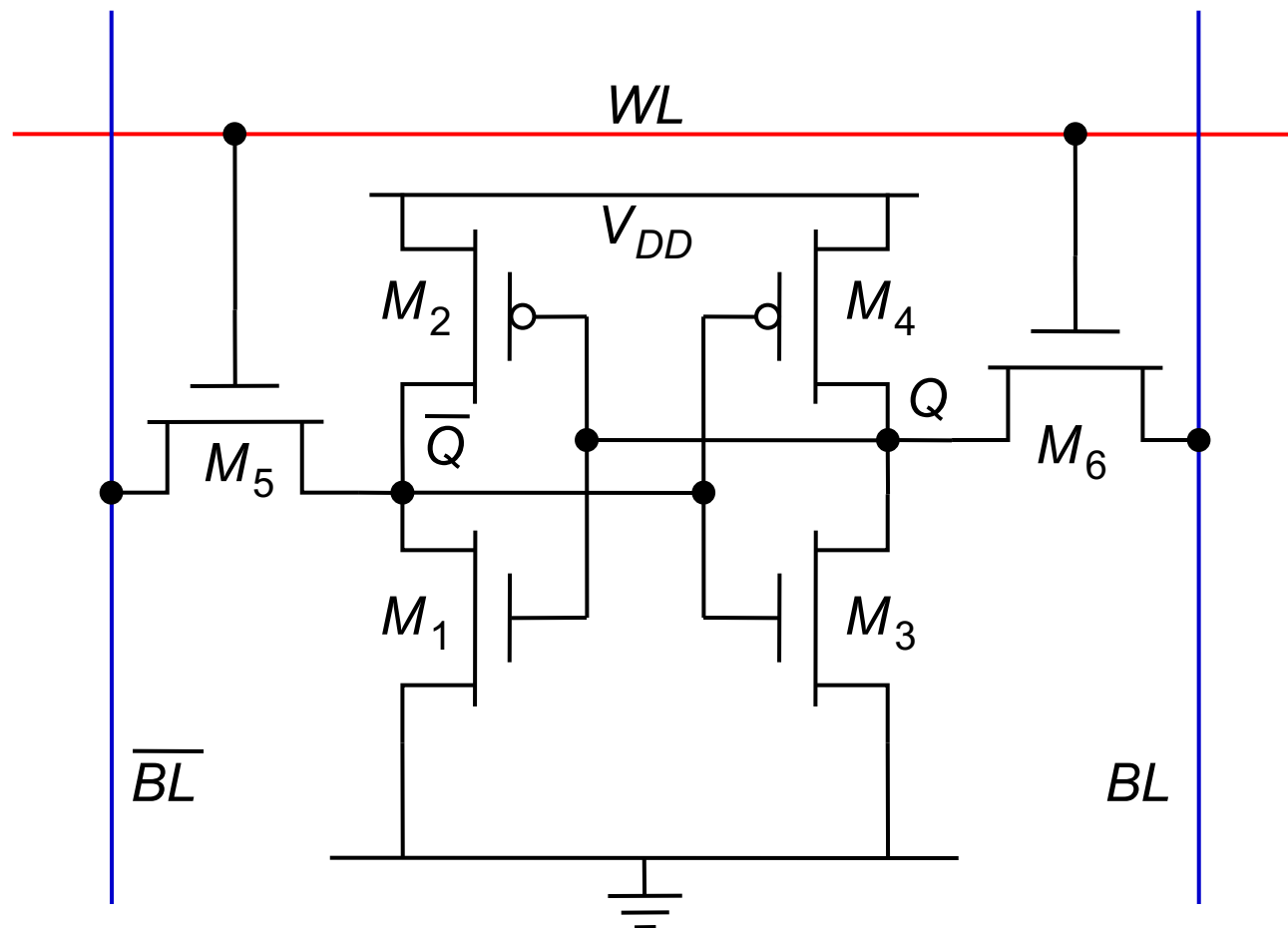
**Periodic refresh required**

**Small (1-3 transistors/cell)**

**Slower**

**Single Ended**

# SRAM 6T Cell

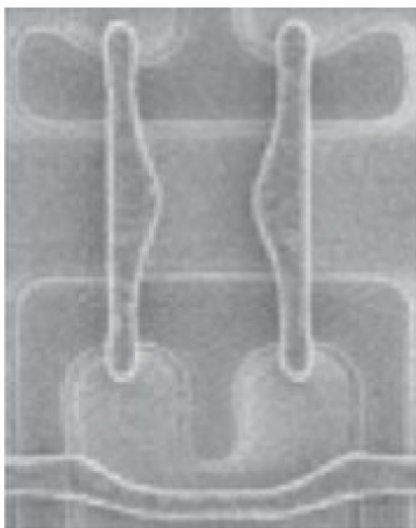
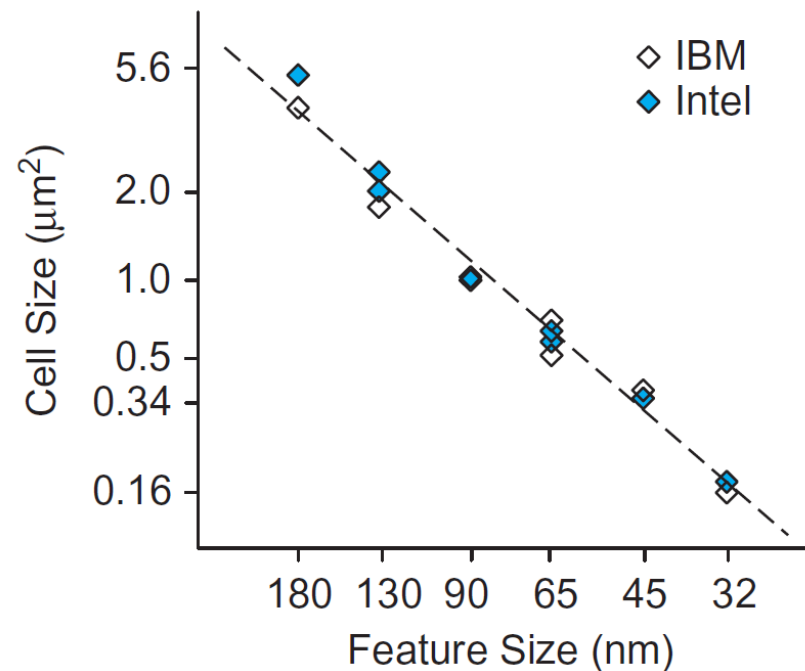


Push Rule: special design rule for SRAM Transistors

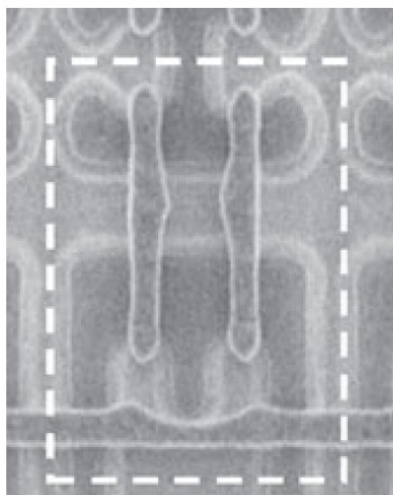


# SRAM Scaling

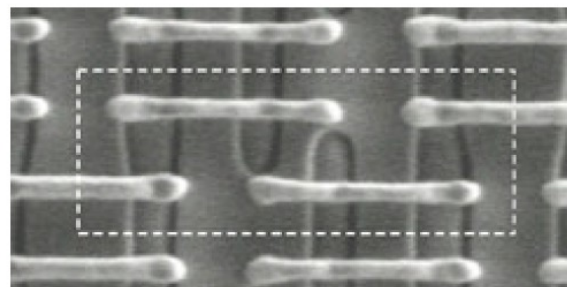
SRAM is the first component for foundry to develop



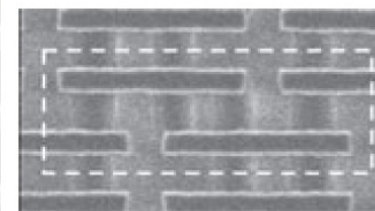
130 nm [Tyagi00]



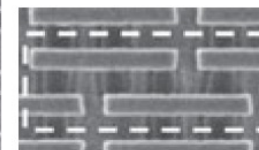
90 nm [Thompson02]



65 nm [Bai04]

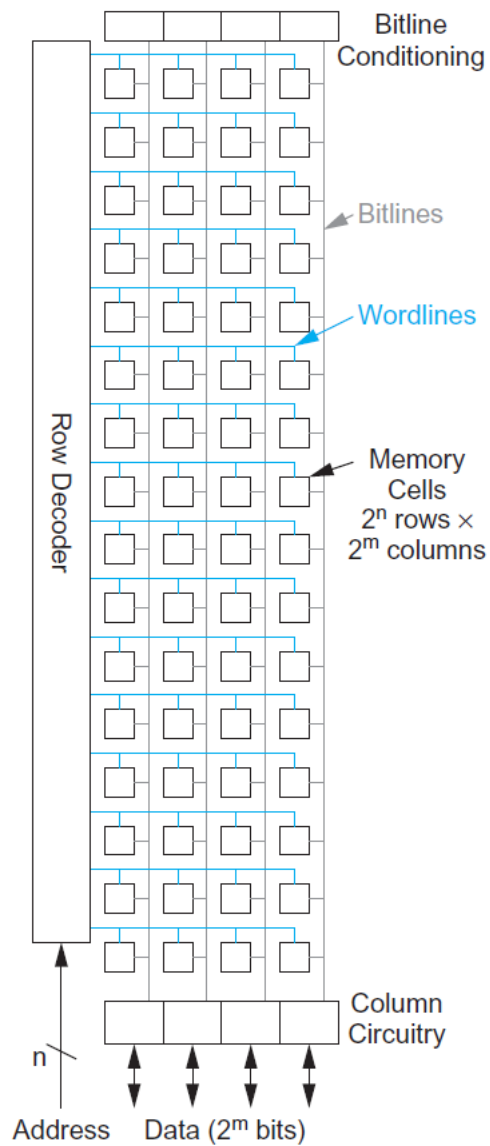


45 nm [Mistry07]

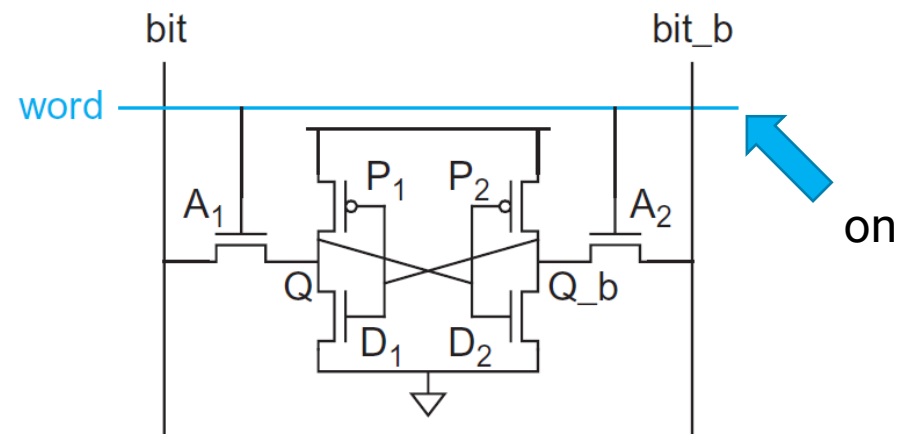


32 nm [Natarajan08]

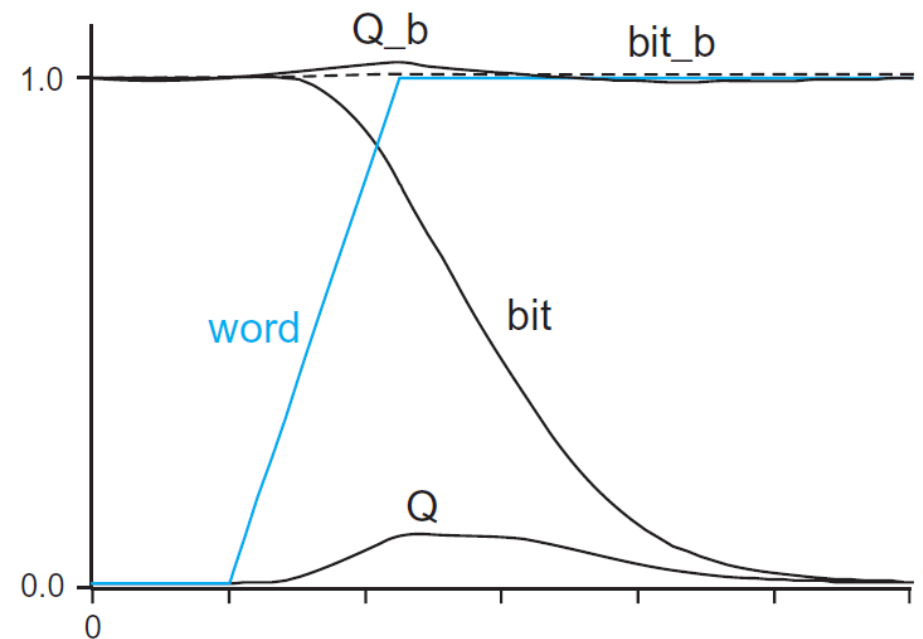
# SRAM Bitcell Array



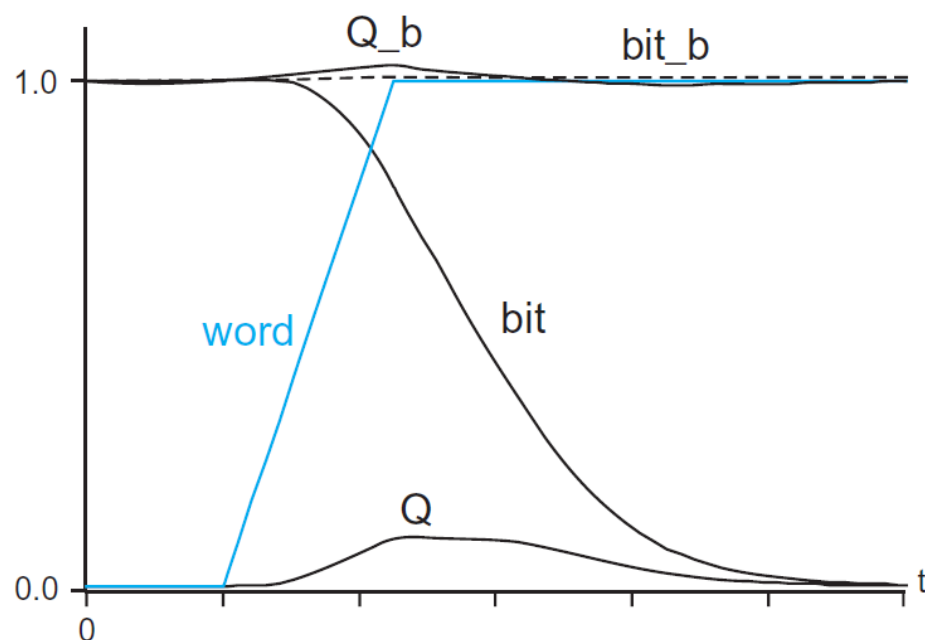
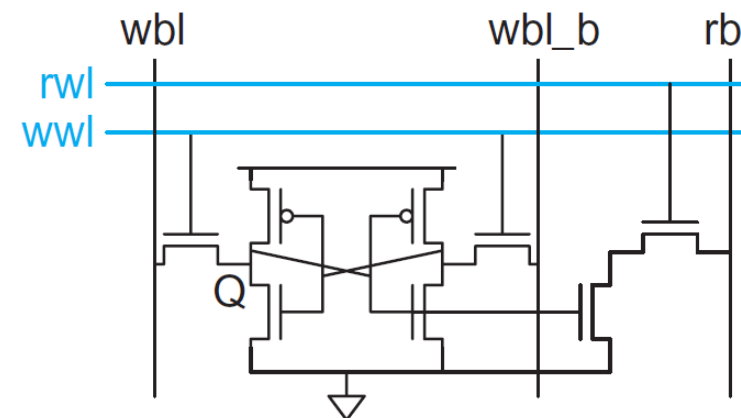
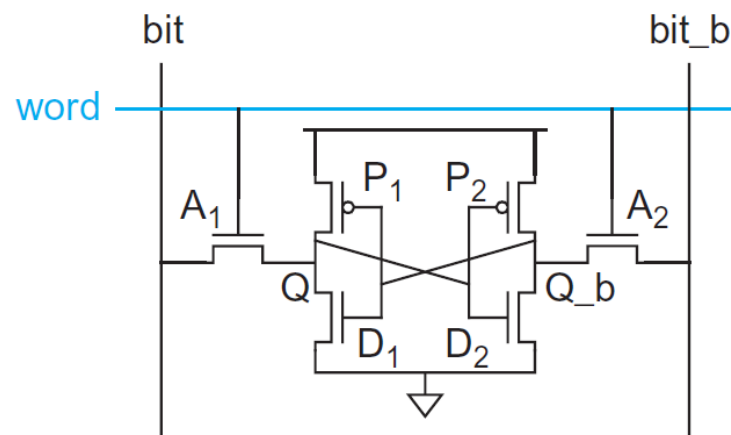
Read Operation:



Timing:



# 8T SRAM



- Advantage: reduce **read disturbance**
- Disadvantage: Too large
- **Read disturbance:**
  - Unexpectedly change bitcell data when read

## ☐ **STATIC (SRAM)**

**Data stored as long as supply is applied**

**Large (6 transistors/cell)**

**Fast**

**Differential**

## ☐ **DYNAMIC (DRAM)**

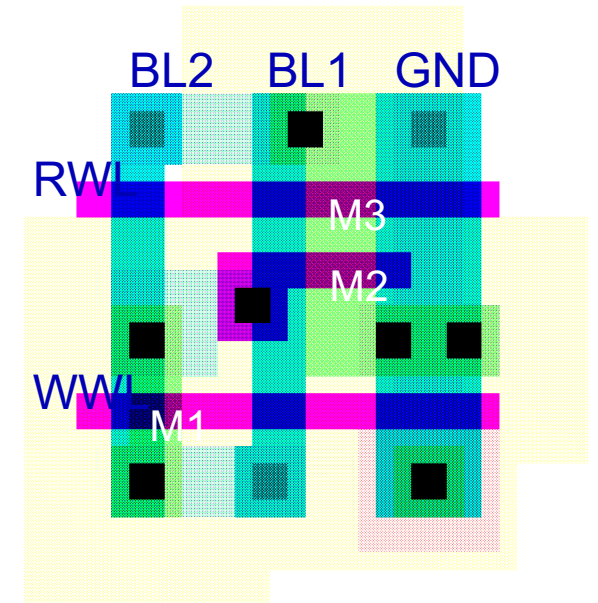
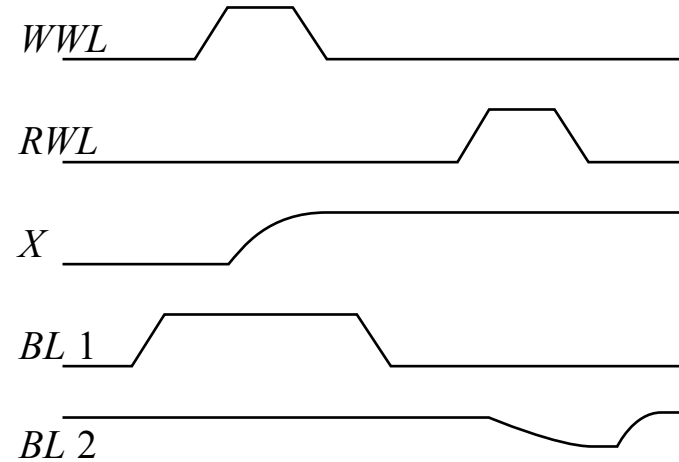
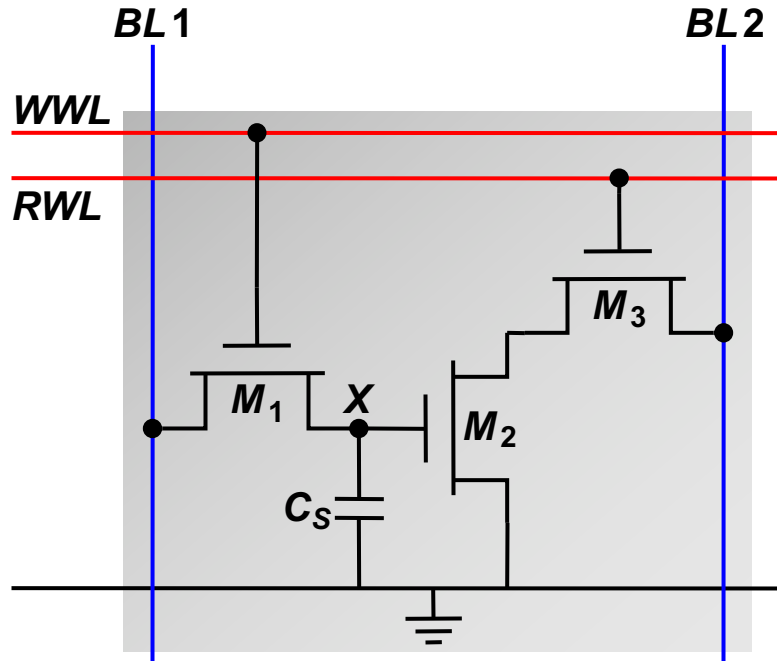
**Periodic refresh required**

**Small (1-3 transistors/cell)**

**Slower**

**Single Ended**

# DRAM Cell 3T



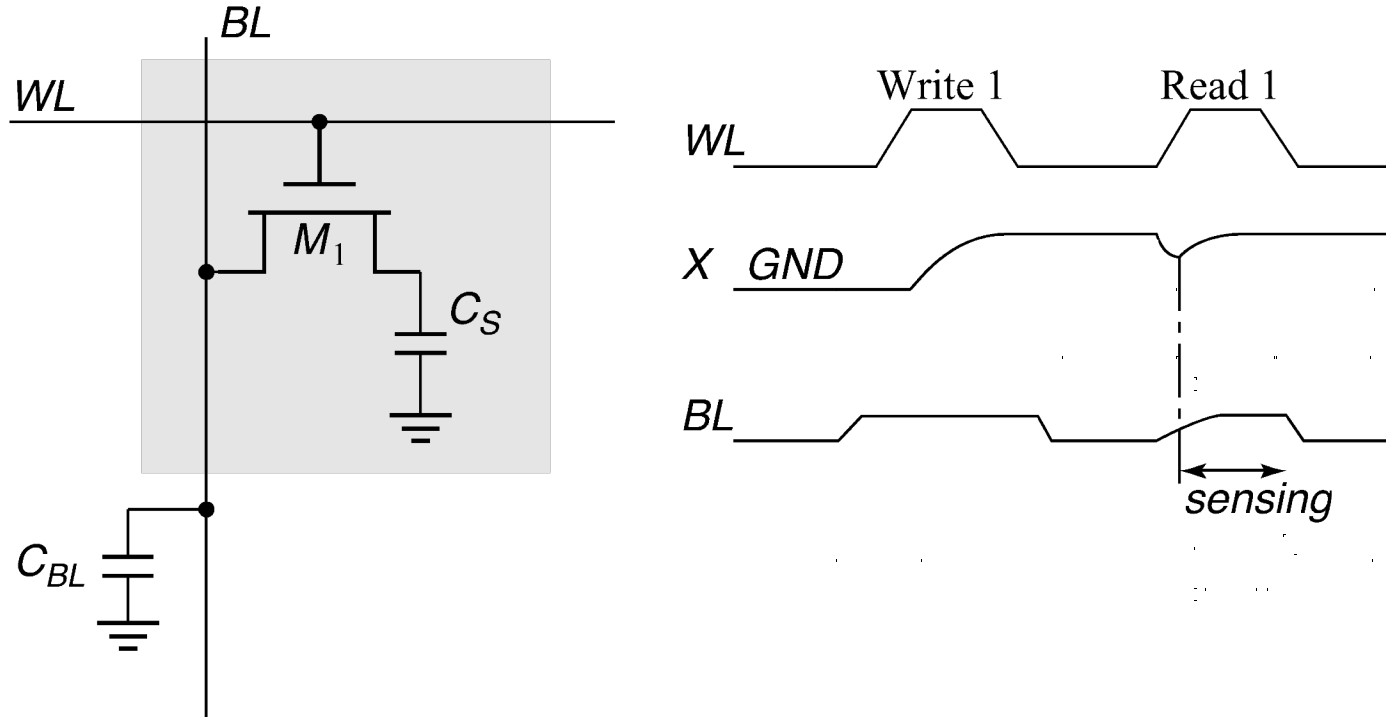
No constraints on device ratios

Reads are non-**destructive**

Value stored at node X when writing a “1” =  $V_{WWL} - V_{Tn}$

**Destructive read:** after reading, the data bit changes with 100% probabilities

# 1T 1R DRAM Cell



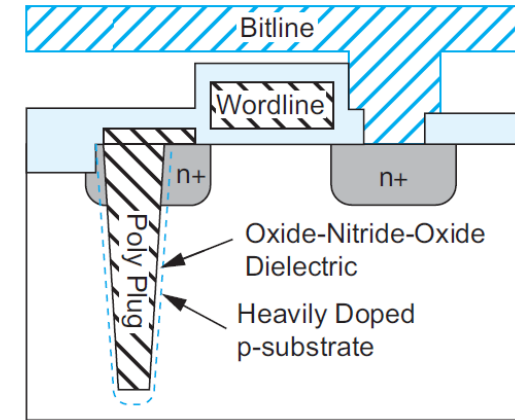
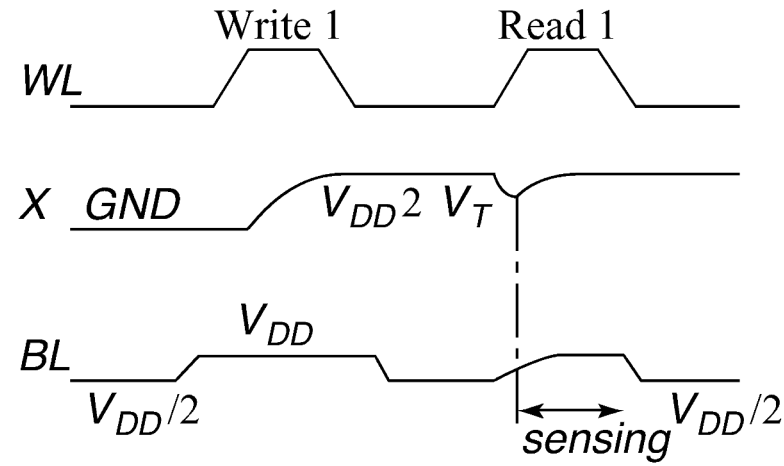
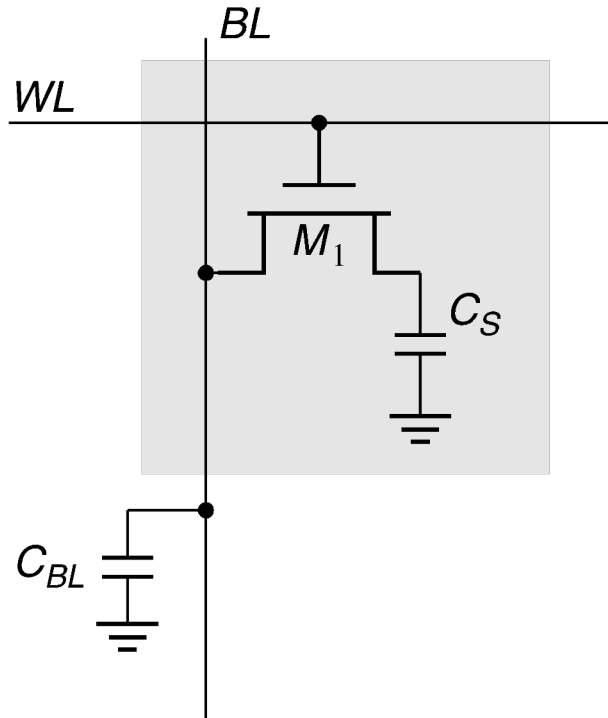
**Write:**  $C_S$  is charged or discharged by asserting WL and BL.

**Read:** Charge redistribution takes places between bit line and storage capacitance

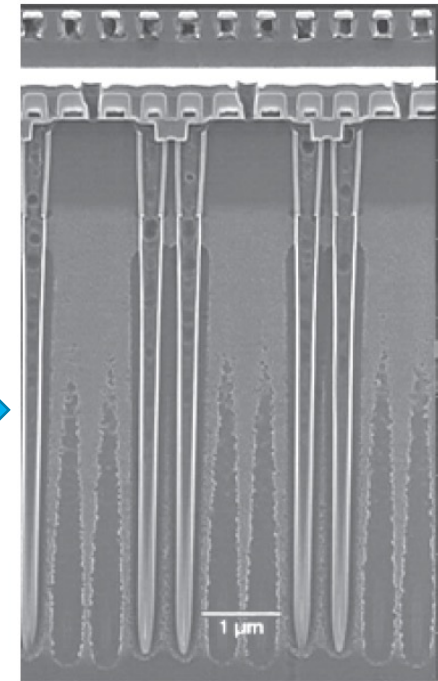
$$\Delta V = V_{BL} - V_{PRE} = V_{BIT} - V_{PRE} \frac{C_S}{C_S + C_{BL}}$$

**Voltage swing is small; typically around 250 mV.**

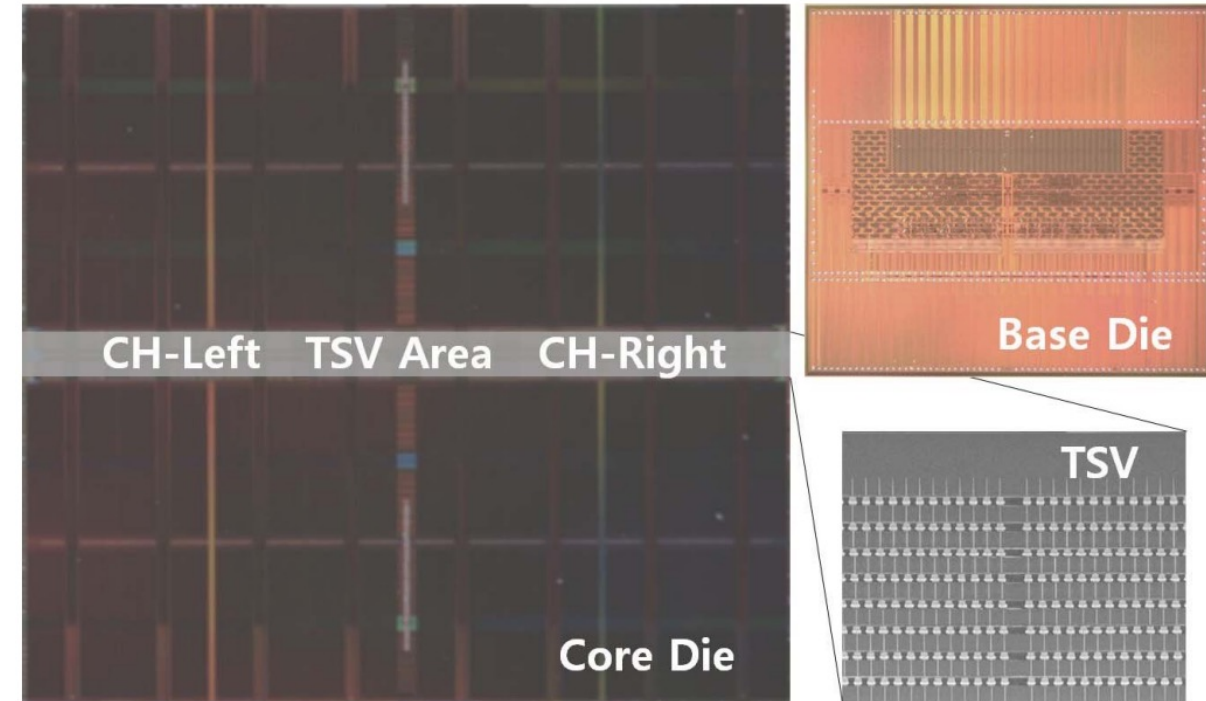
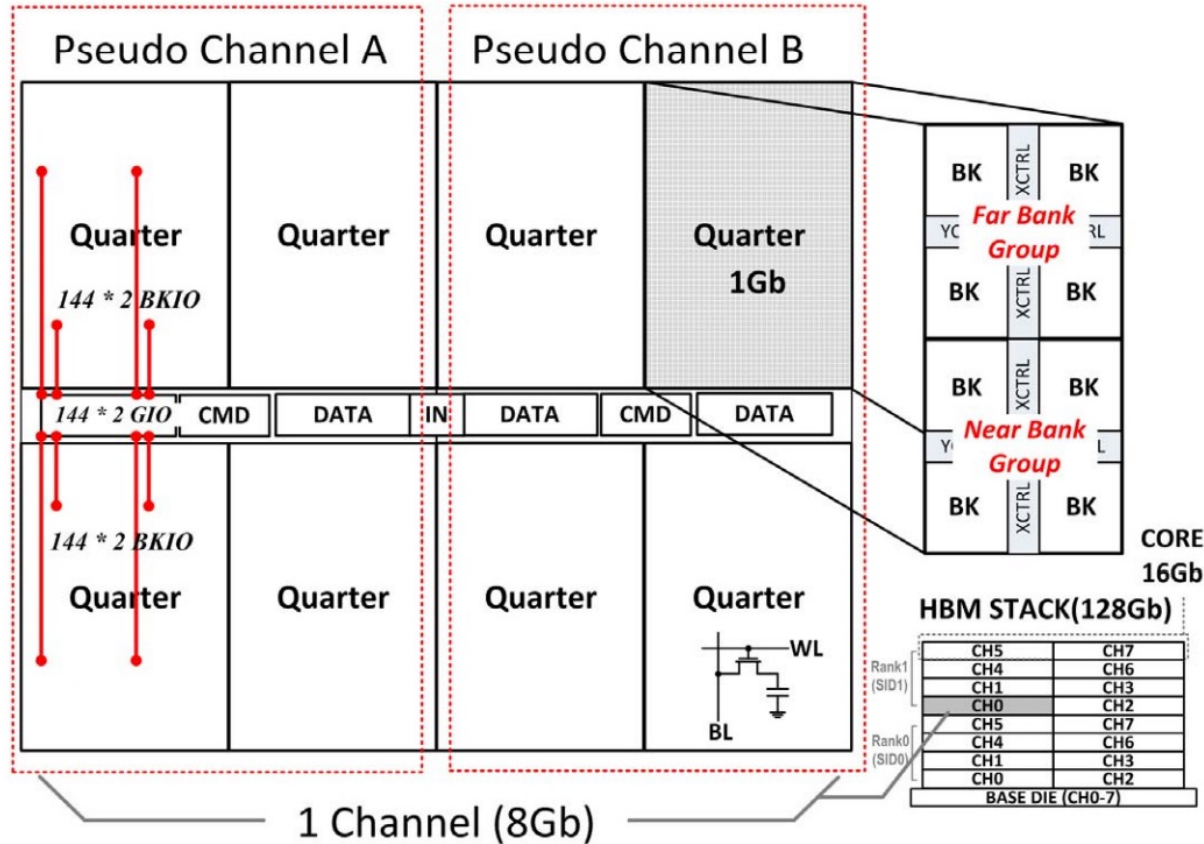
# 1T1R DRAM Cell



- Often offer 10~20 times higher density than SRAM
- Trench capacitor is often in specialized process



# Better Density – 3D Integration



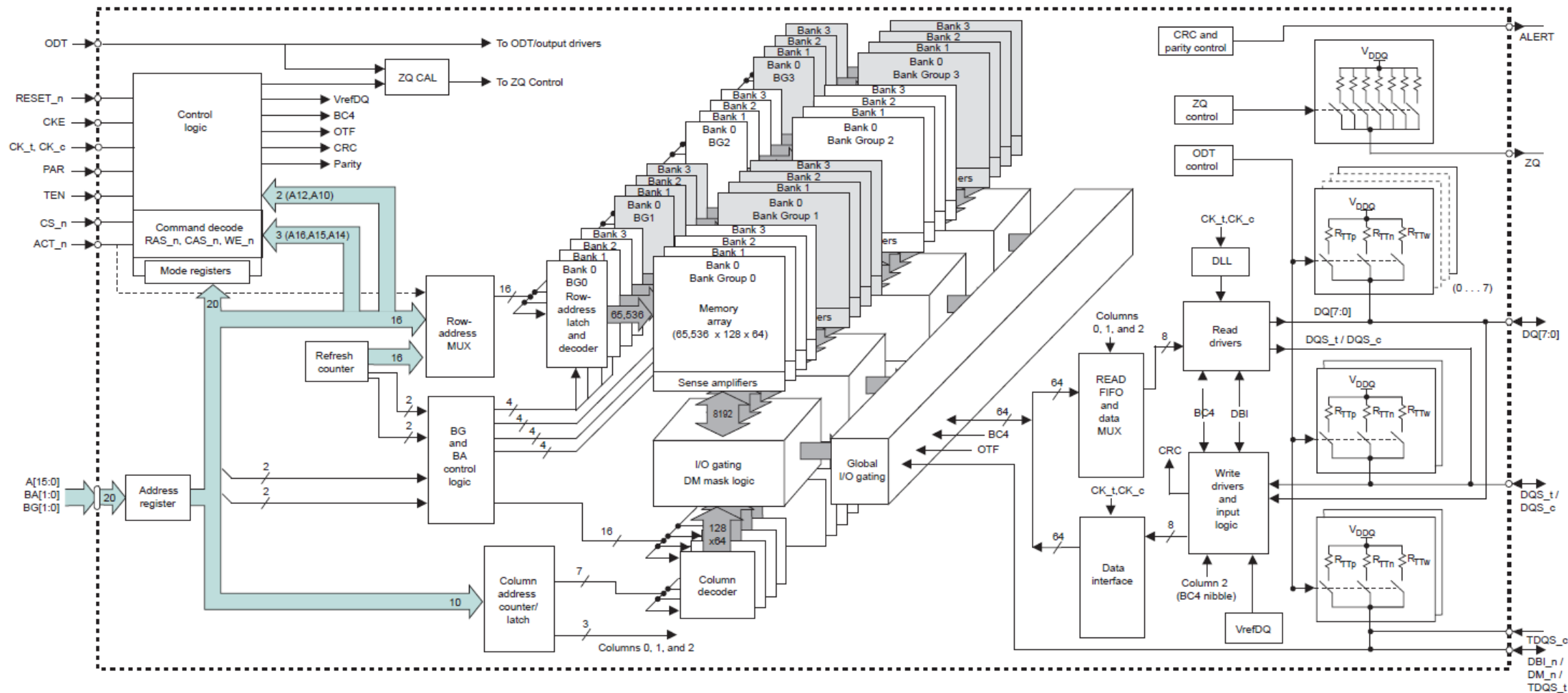
Lee, Dong Uk, et al. "22.3 A 128Gb 8-high 512GB/s HBM2E DRAM with a pseudo quarter bank structure, power dispersion and an instruction-based at-speed PMBIST." *2020 IEEE International Solid-State Circuits Conference-(ISSCC)*. IEEE, 2020.



- eDRAM: embedded DRAM
- DRAM special process (thick oxide/high threshold) is too slow as logic platform
- eDRAM process incorporates compact-size of capacitors to be compatible with processes for logic (regular threshold transistors)

# A Practical DRAM Product

Figure 3: 1 Gig x 8 Functional Block Diagram



Source: Micron

CPUs can also use **registers**, **caches** and **scratchpad memory**

# Register Files & Cache

Register file: an array of registers

Cache: “transparent memory” to avoid excessive access to DRAM

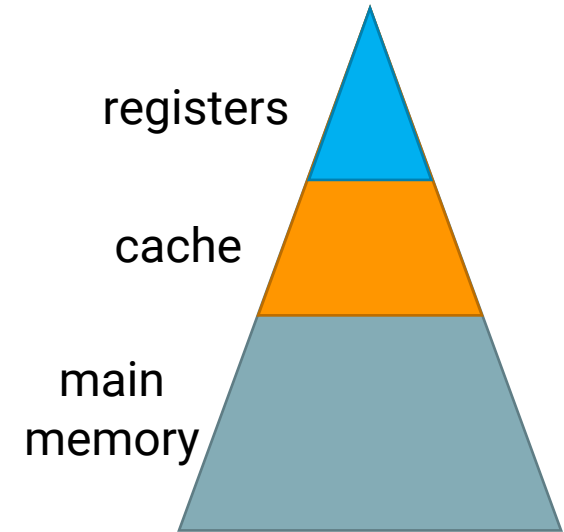
Registers and Caches are often made of SRAM

```
int a , b , c;  
a = 1;  
b = 2;  
C = a + b;
```

compiler



where to store a, b and c?

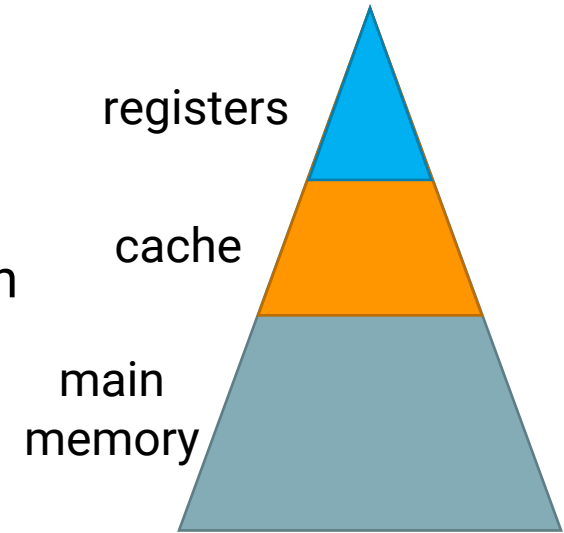


- If registers are enough, they are all in registers
- If registers are not enough, they need to enter main memory (with an address)
- If “cache hit” happens, they will not go off-chip (large latency/low access bandwidth)

# Register files

```
module picorv32_regs (  
    input clk, wen,  
    input [5:0] waddr,  
    input [5:0] raddr1,  
    input [5:0] raddr2,  
    input [31:0] wdata,  
    output [31:0] rdata1,  
    output [31:0] rdata2  
);  
    reg [31:0] regs [0:30];  
  
    always @(posedge clk)  
        if (wen) regs[~waddr[4:0]] <= wdata;  
  
    assign rdata1 = regs[~raddr1[4:0]];  
    assign rdata2 = regs[~raddr2[4:0]];  
endmodule
```

- Is this synthesizable? Yes!
- Do we use synthesis flow to generate memory? Yes!
- Sometimes we use this, often we use full-custom flow to design register files

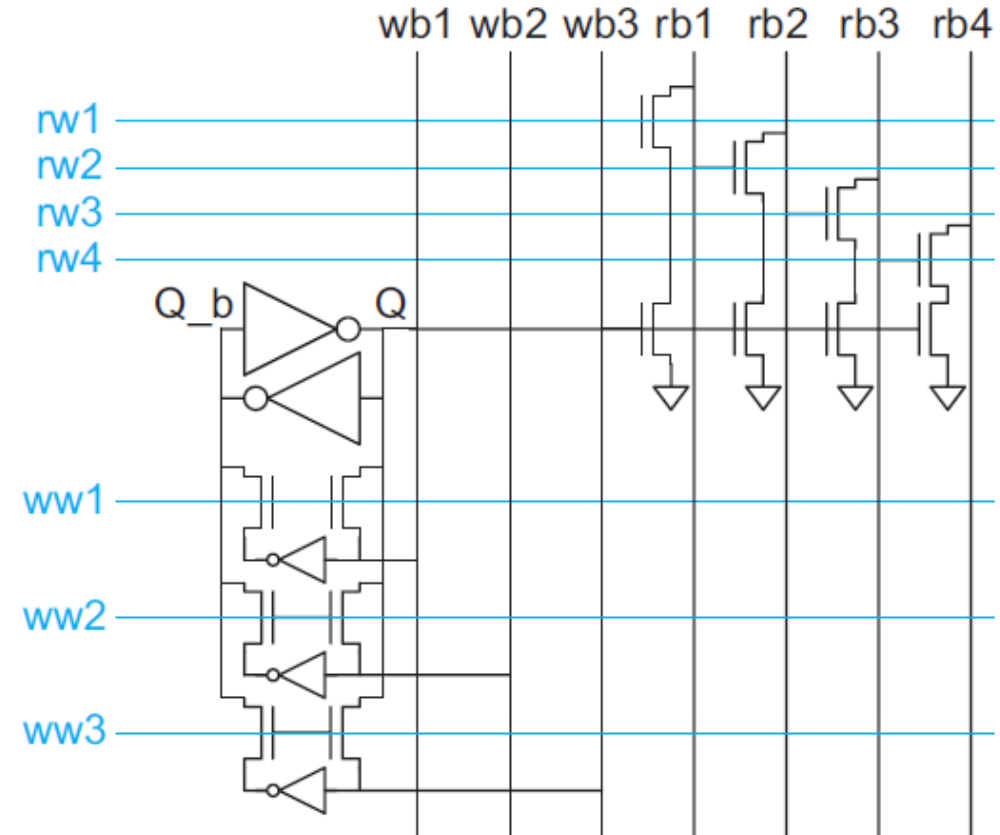


# Register files

Made from SRAM?

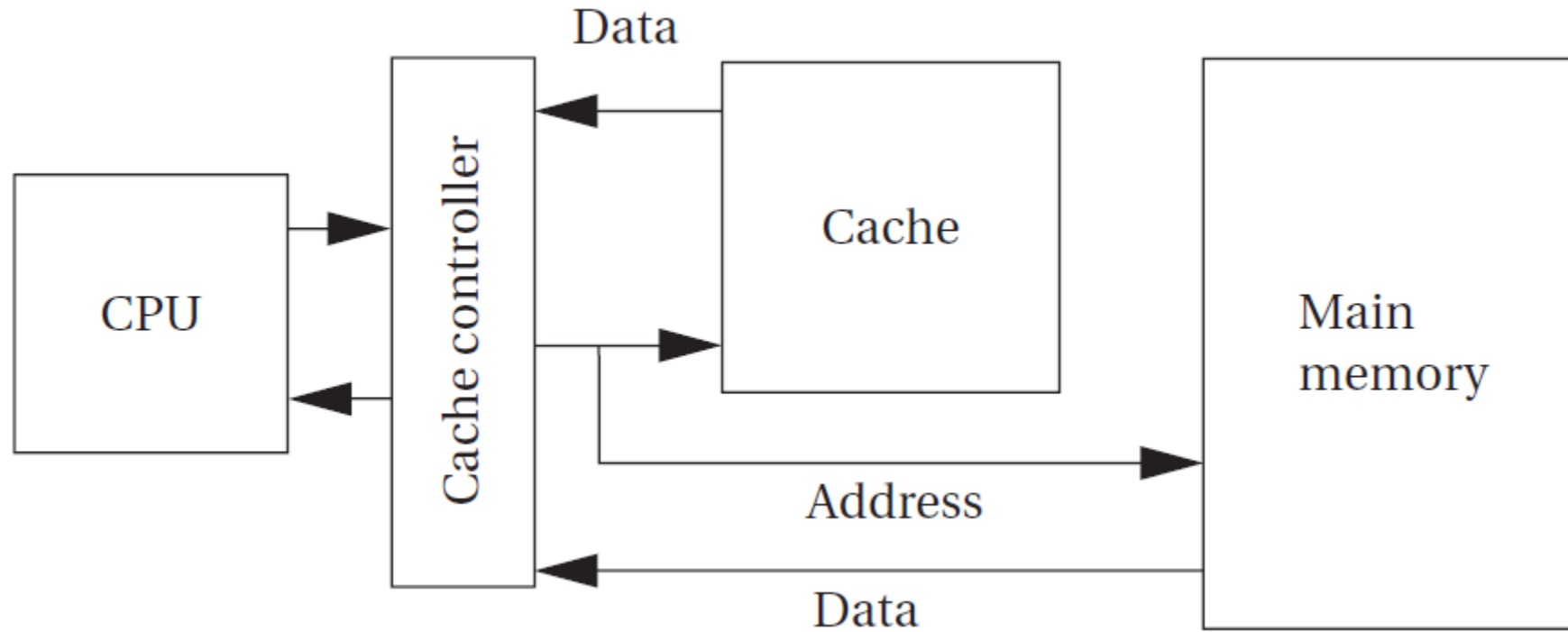
Requirement: Multiport Read/Write

- How to use this cell to build large array of registers and even a register file?
- ww1, ww2, ww3 control need to be one-hot



Multiport SRAM cell

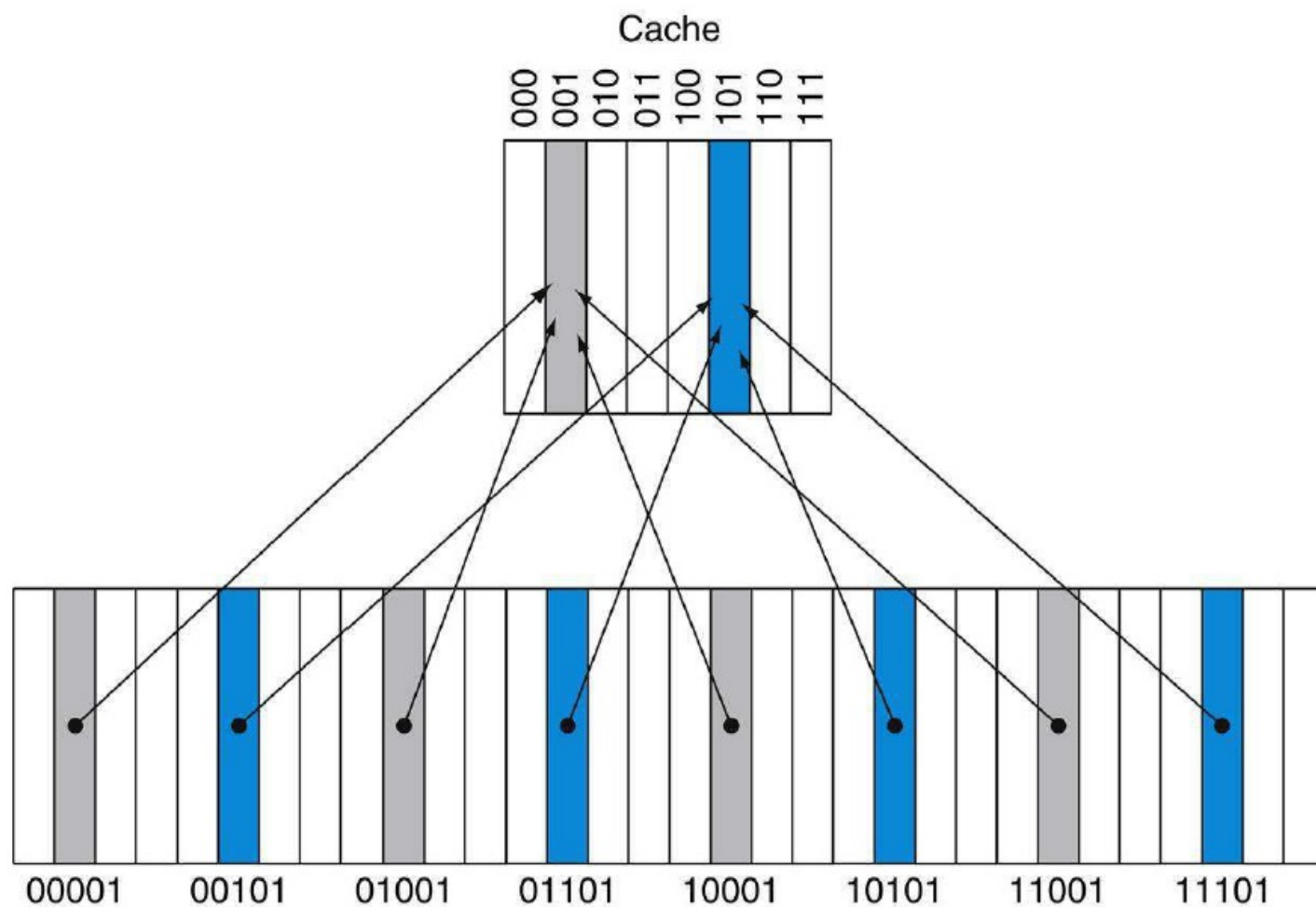
# Cache



CPU keeps asking if the data is in the cache:

- If yes, it is a cache hit
- If no, it is a cache miss

# Direct Map



Tag: higher 2b address as the tag

To clarify whether the requested word in memory is in the cache

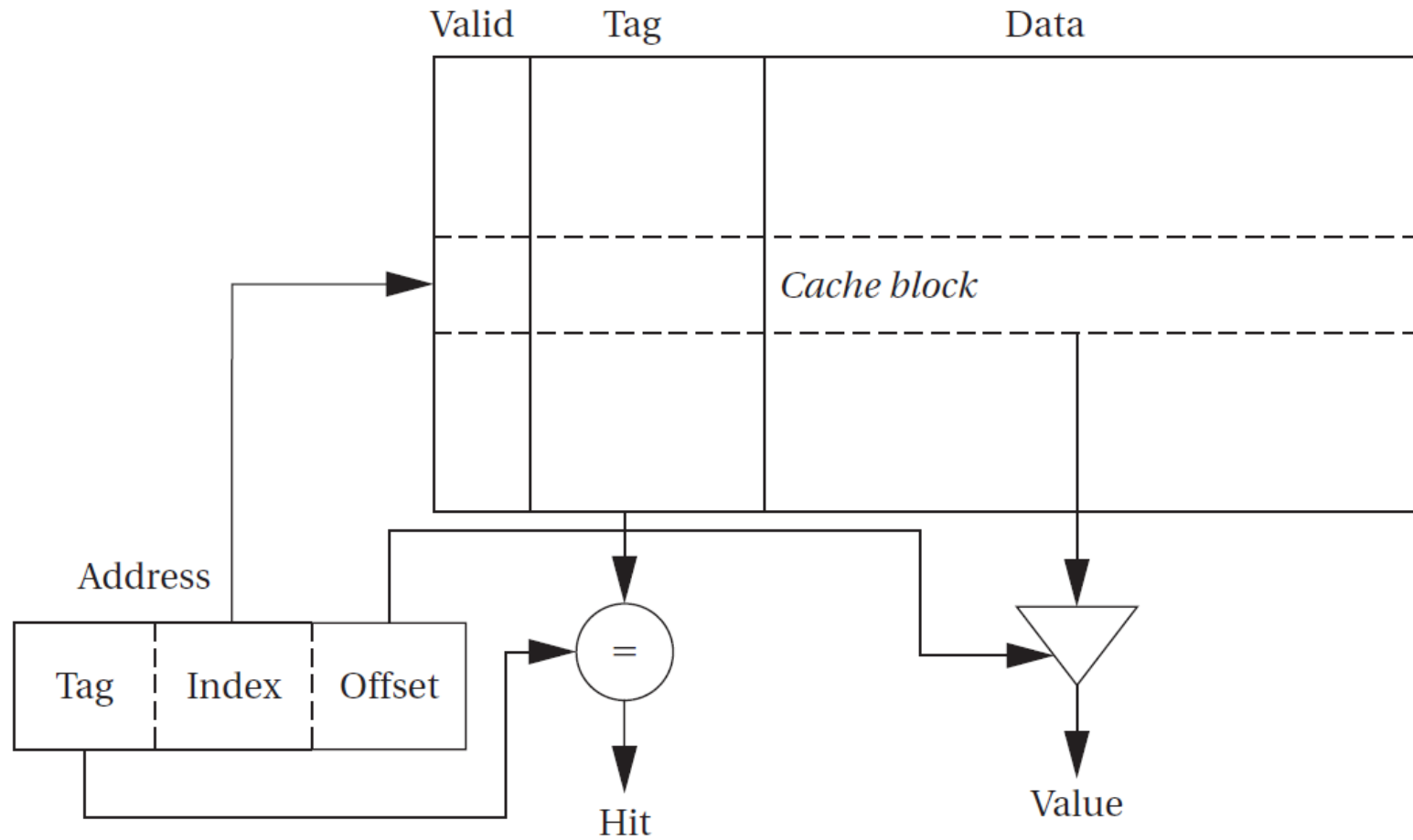




# Inside A Cache

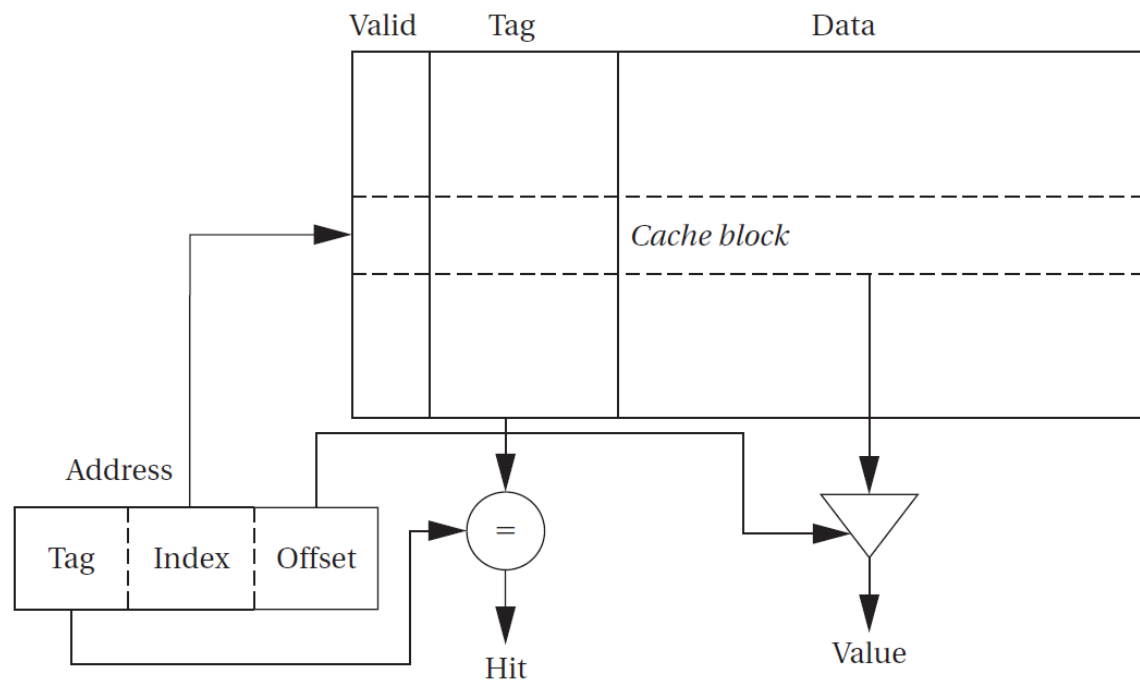


北京大学  
PEKING UNIVERSITY

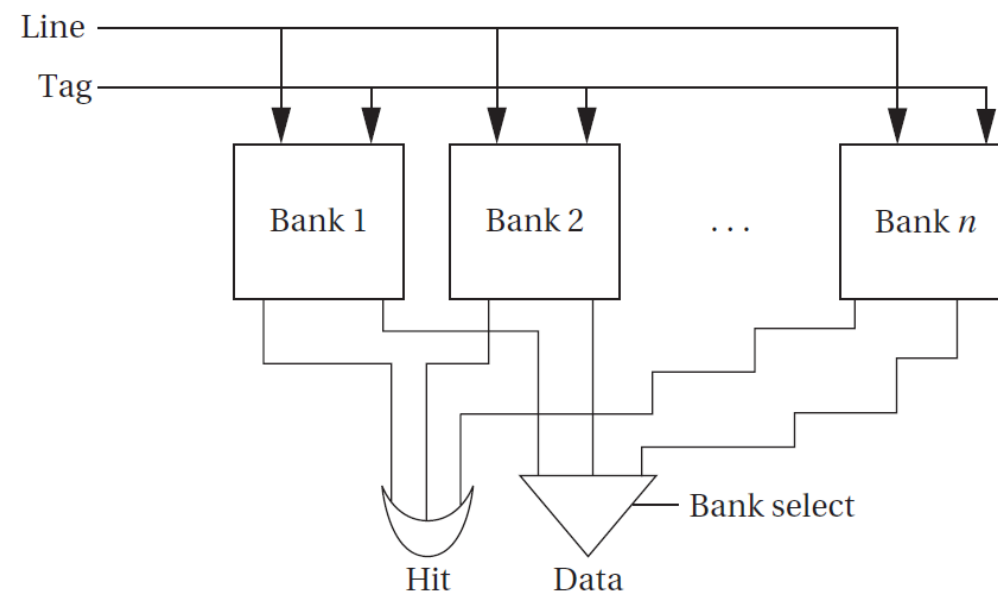


Content-addressable memory (CAM) / associate memory

# Direct-associativity & Set-associativity



direct-associative



n-way set-associative

# Example of direct- and set-associativity

**One-way set associative  
(direct mapped)**

Block	Tag	Data
0		
1		
2		
3		
4		
5		
6		
7		

**Two-way set associative**

Set	Tag	Data	Tag	Data
0				
1				
2				
3				

**Four-way set associative**

Set	Tag	Data	Tag	Data	Tag	Data	Tag	Data
0								
1								

**Eight-way set associative (fully associative)**

Tag	Data	Tag	Data	Tag	Data	Tag	Data	Tag	Data	Tag	Data	Tag	Data	Tag	Data

Set: increase the cache hit probability

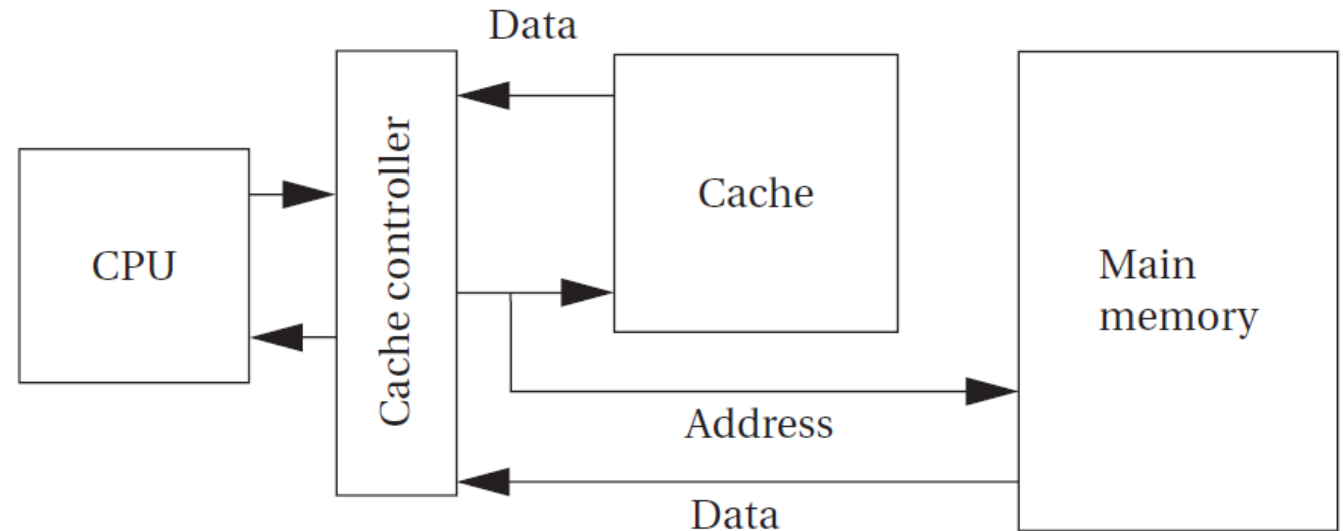
Assumption/Logic behind:  
Cache miss leads to very long time of  
data movement

# Challenges for Cache Design

Definition: Scratchpad Memory is just embedded “memory”.

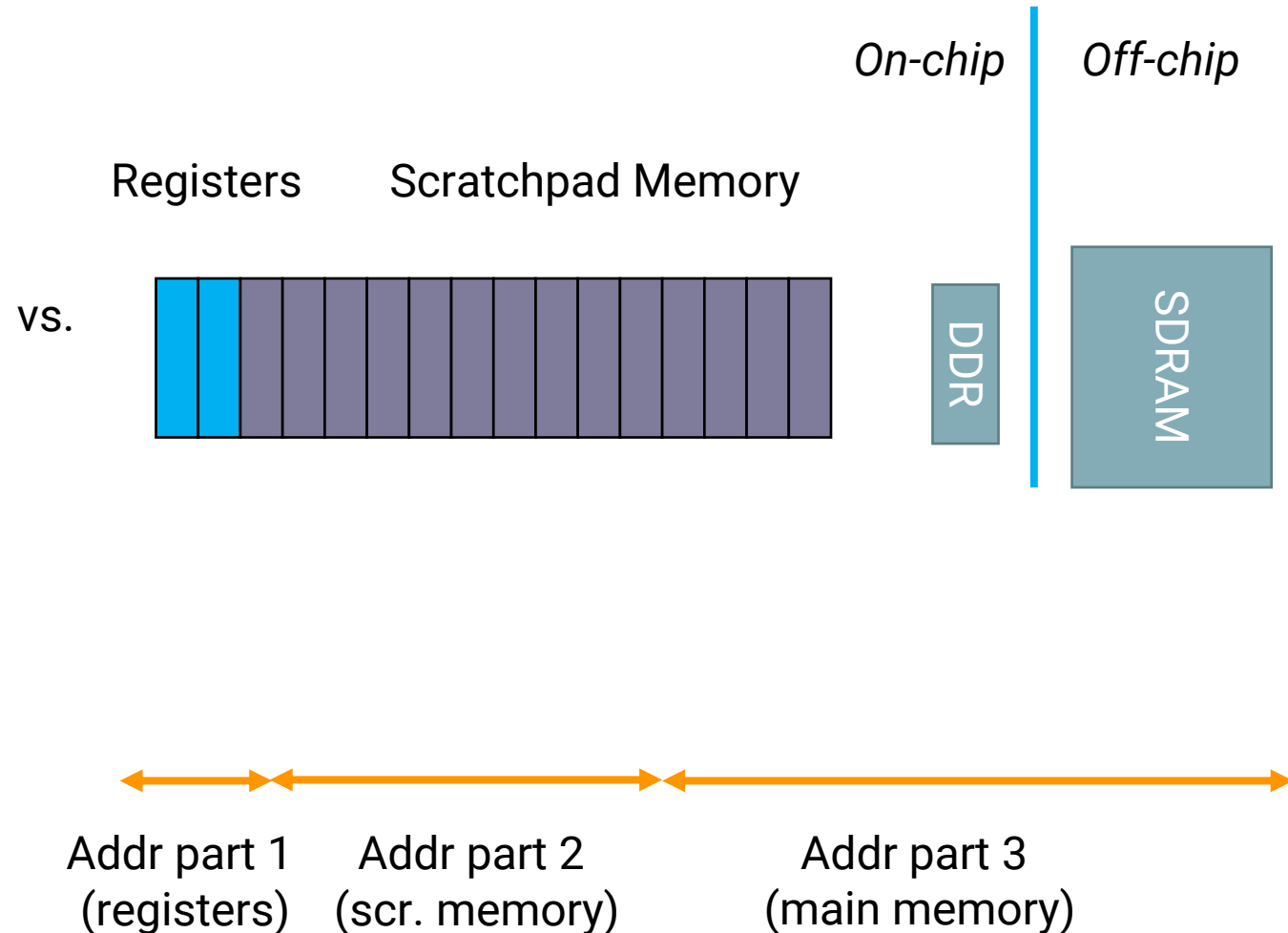
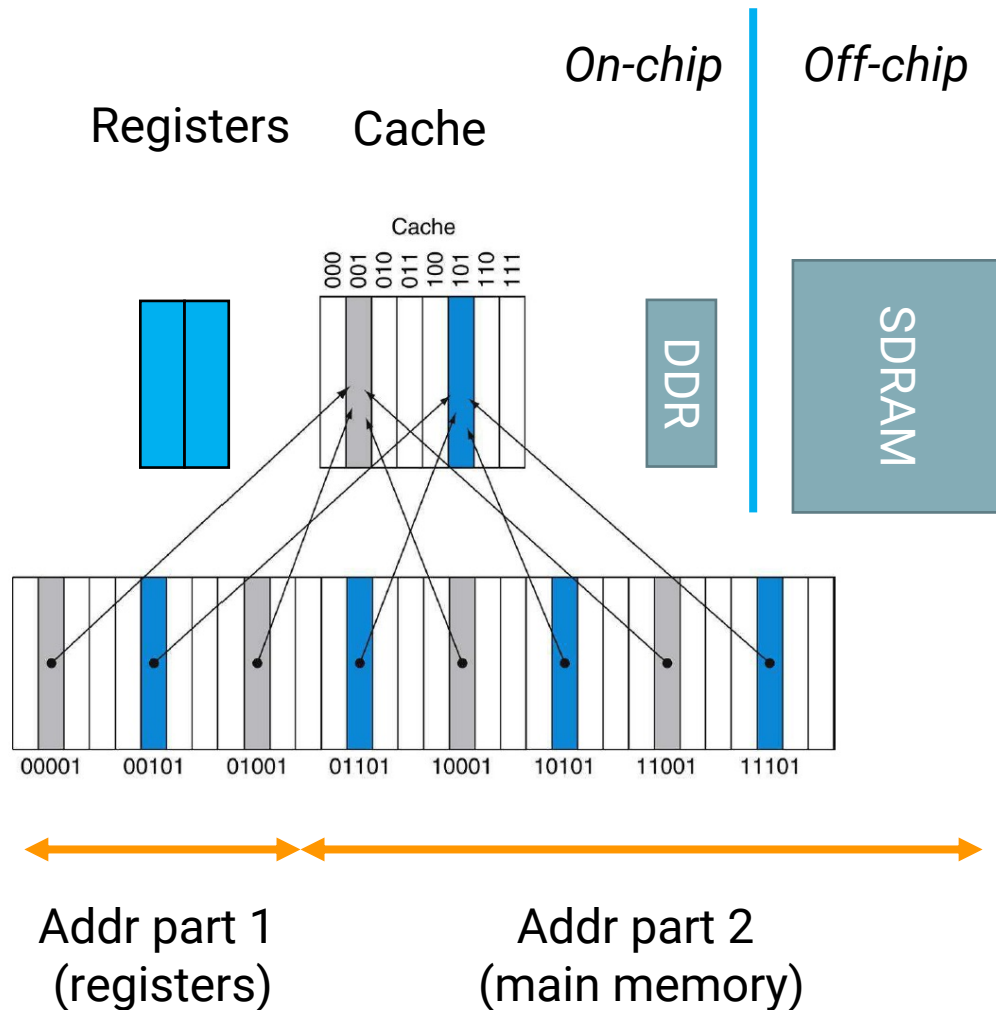
Embedded memory: memories that are on the chip, i.e. “integrated memory”.

- Complex mechanism
- Large area overhead
- Stochastic characteristics
  - Cache miss penalty is too large!



# Scratchpad Memory vs. Cache

Definition: Scratchpad Memory is just embedded “memory”.



- Memories
  - Operations: Read, Write
  - Basic circuits: bitcell array, column/row decoders, sense amplifiers (SA)
  - Hierarchy:
    - registers, cache, scratchpad memory, main memory
  - Memory technologies:
    - Transistor-based ROMs, SRAM, DRAM, eNVM (embedded nonvolatile memory)
  - Other concepts:
    - cache miss, cache hit, address space